

A Data-driven Approach to Credible Uncertainty Quantification

Jacob Forbes, Elan Park-Bernstein, Cole Frisch, Justin Loring, Aaron Clark, Vladimir Sobes



THE UNIVERSITY OF
TENNESSEE
KNOXVILLE

*Some figures are based on work of former students: Noah Walton and Jordan Armstrong

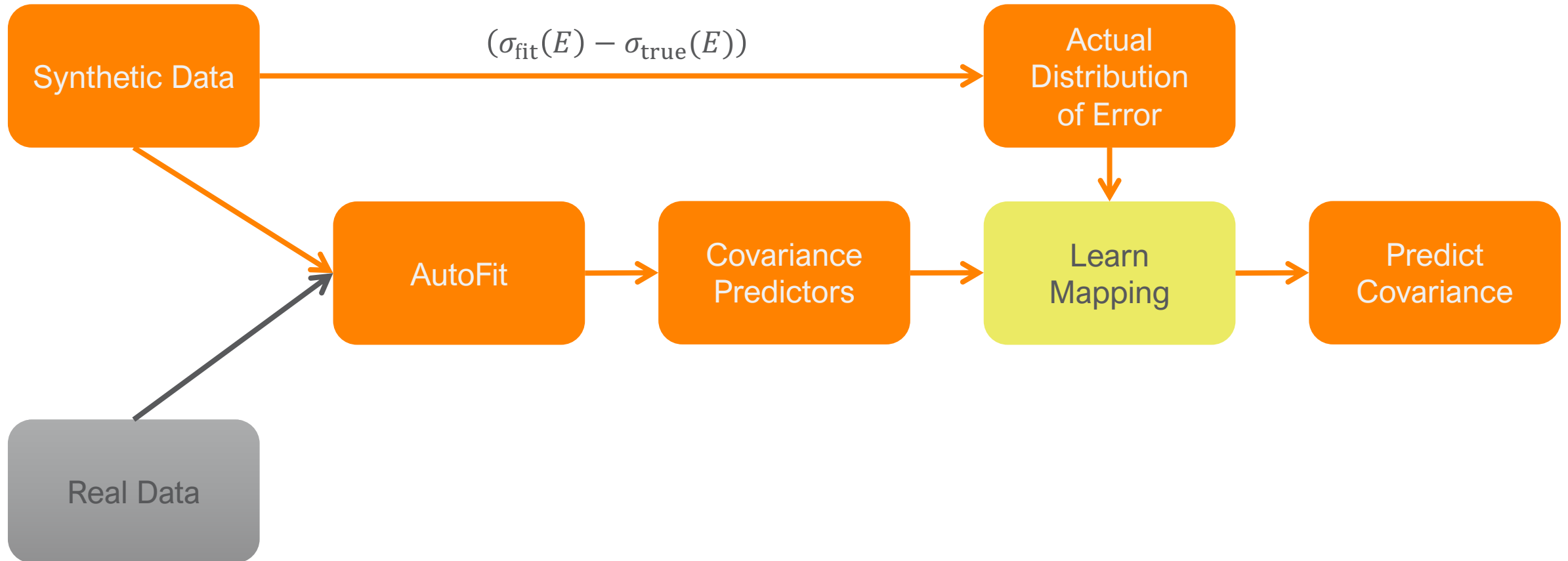
Main findings

Cross section uncertainty $\sim 10\%$ in RRR with good differential data

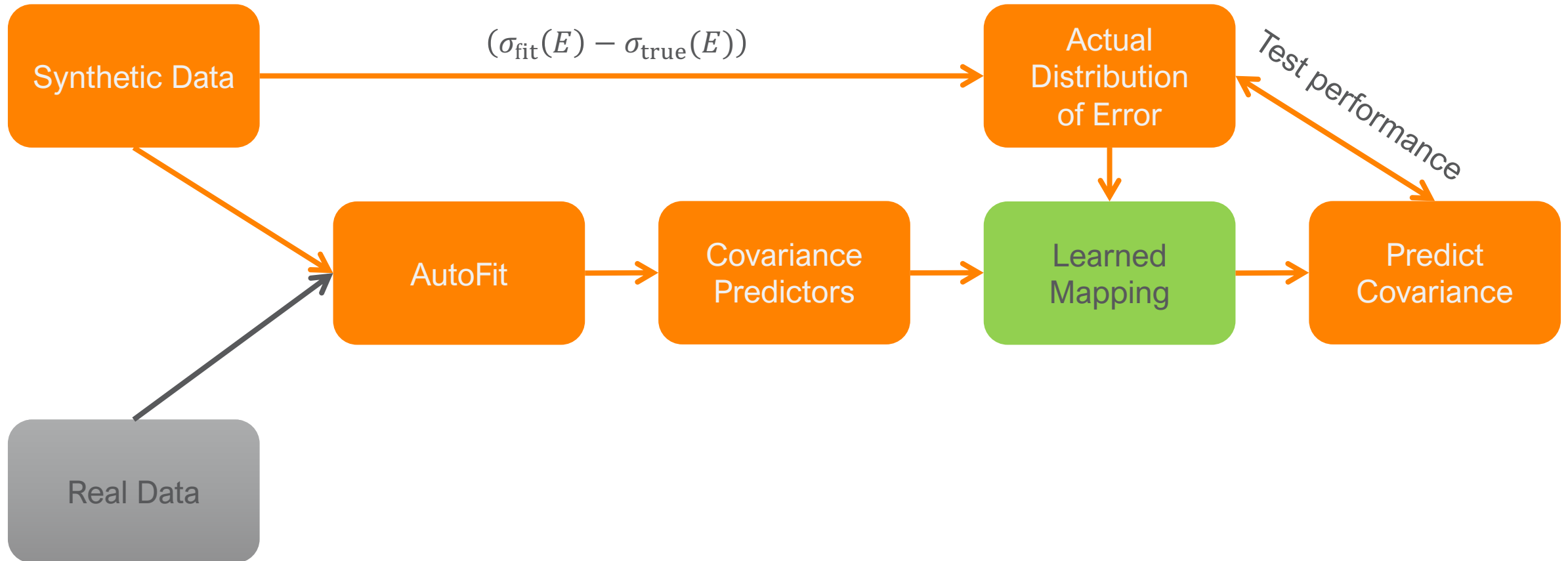
Access to distribution of error

Quantifiable impact on benchmarks / applications

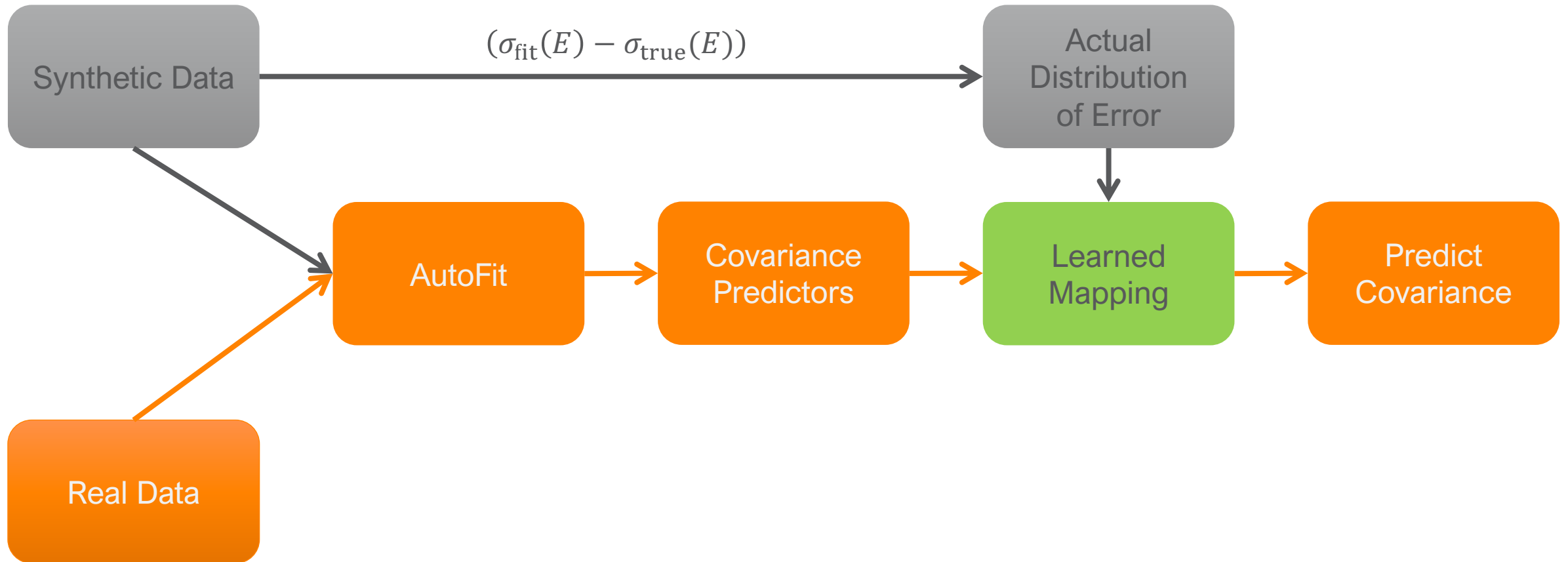
Approach Overview



Approach Overview



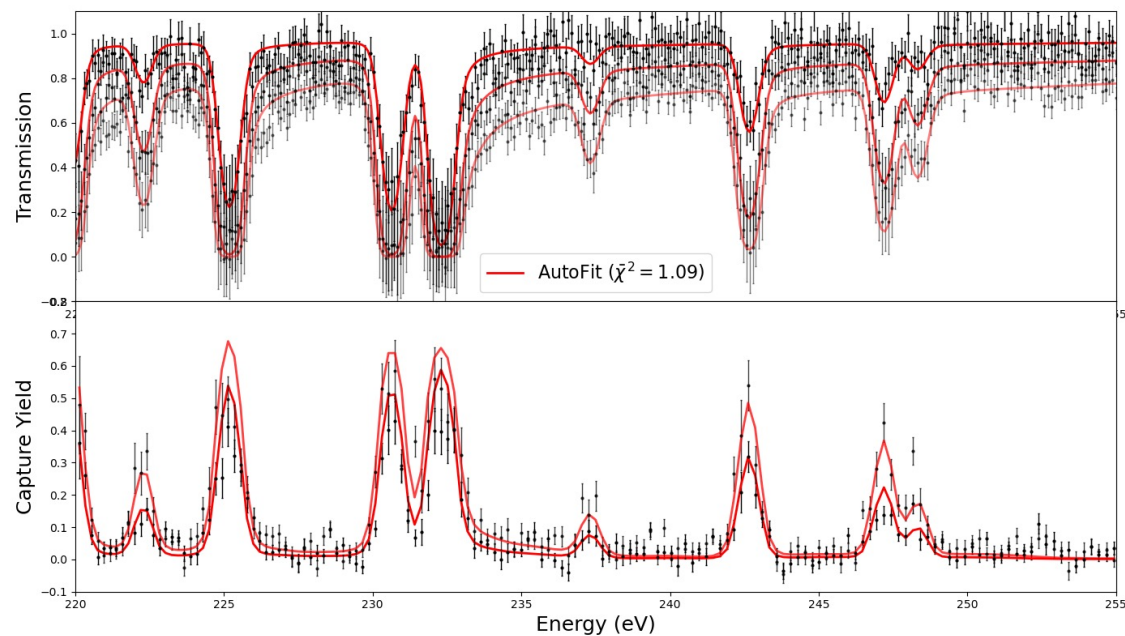
Approach Overview



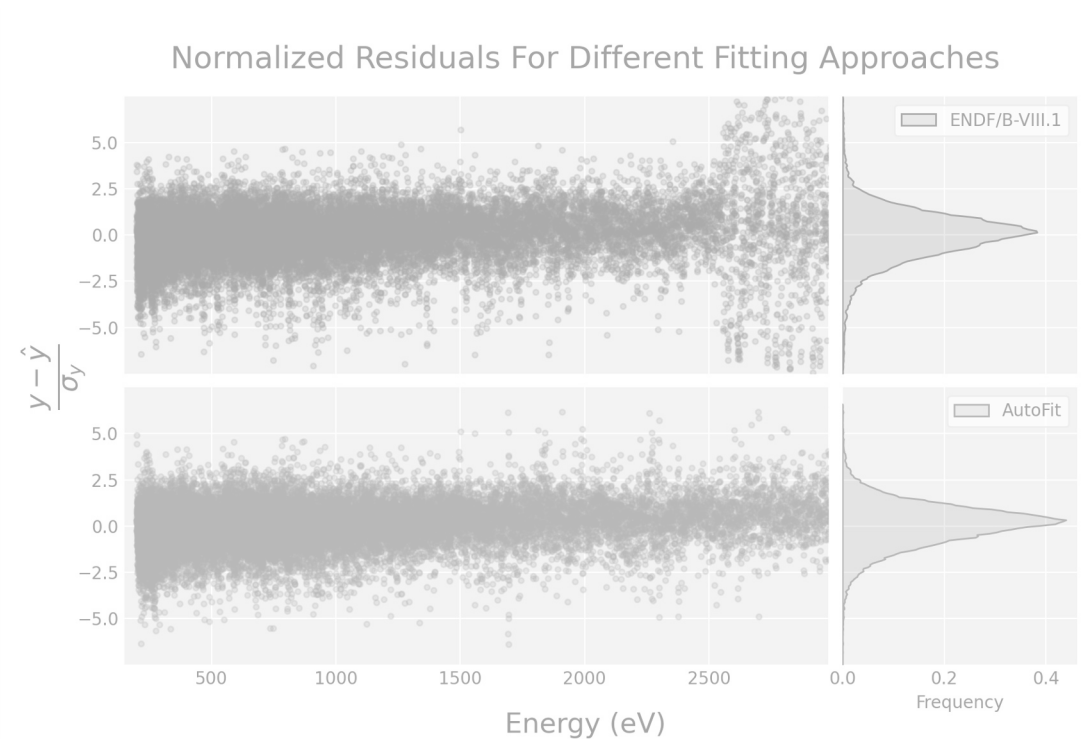
AutoFit Algorithm

Fitting Method	χ^2/N_{data}
AutoFit	1.354
ENDF/B-VIII.1	1.698
ENDF/B-VIII.1 Fit	1.581

Automated, deterministic, repeatable



χ^2 fitting on par with human evaluators

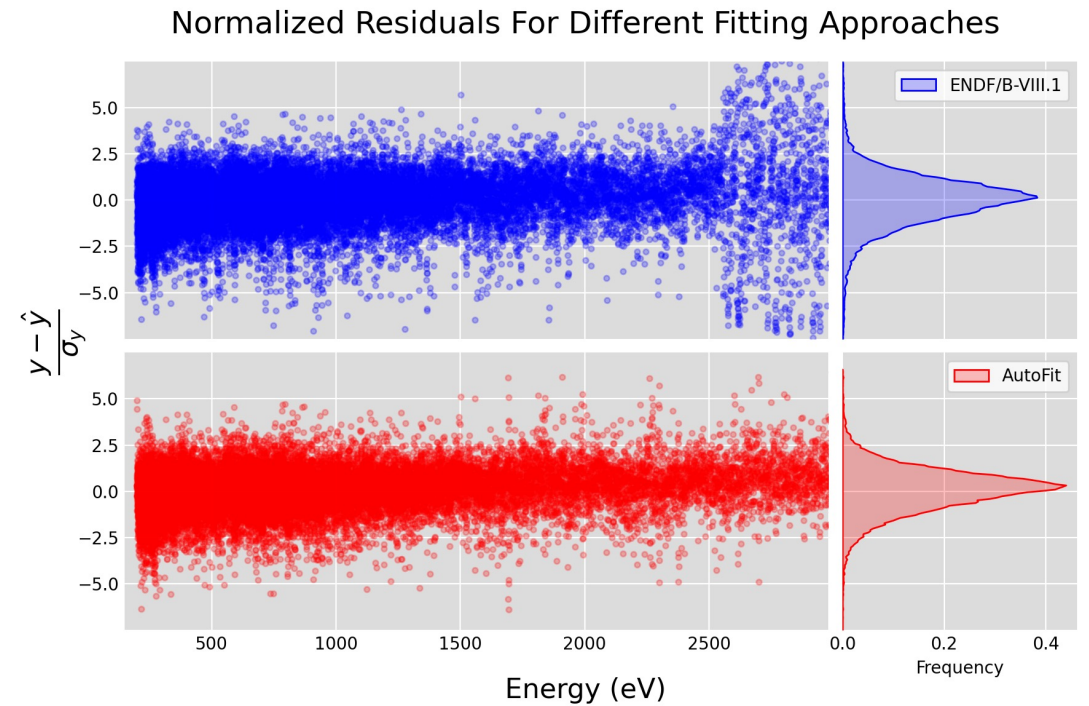
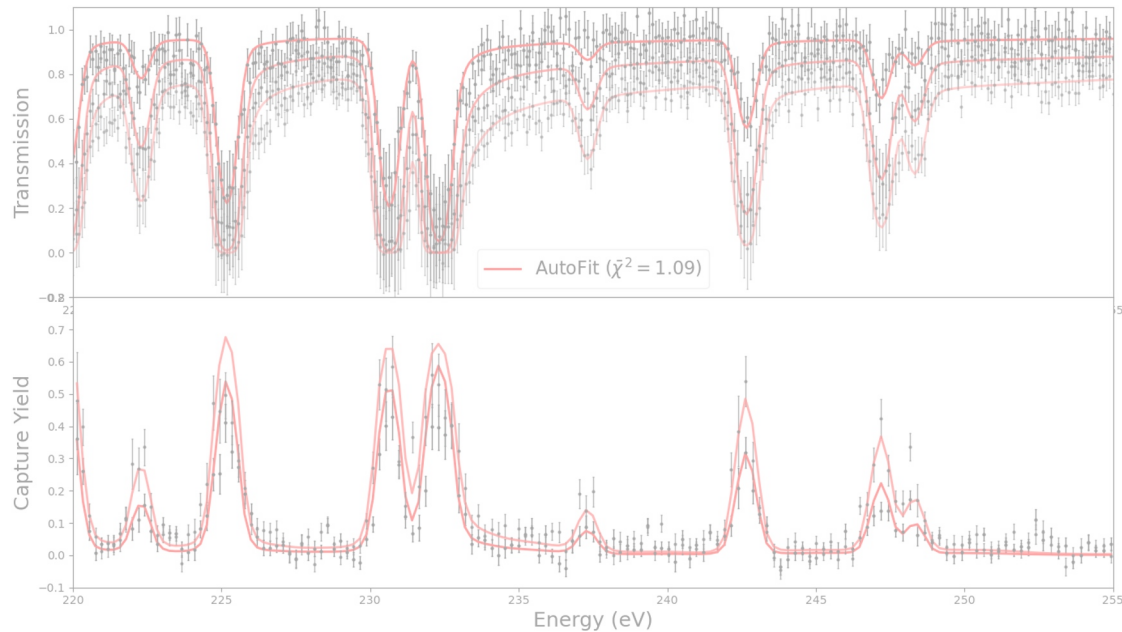


AutoFit Algorithm

Fitting Method	χ^2/N_{data}
AutoFit	1.354
ENDF/B-VIII.1	1.698
ENDF/B-VIII.1 Fit	1.581

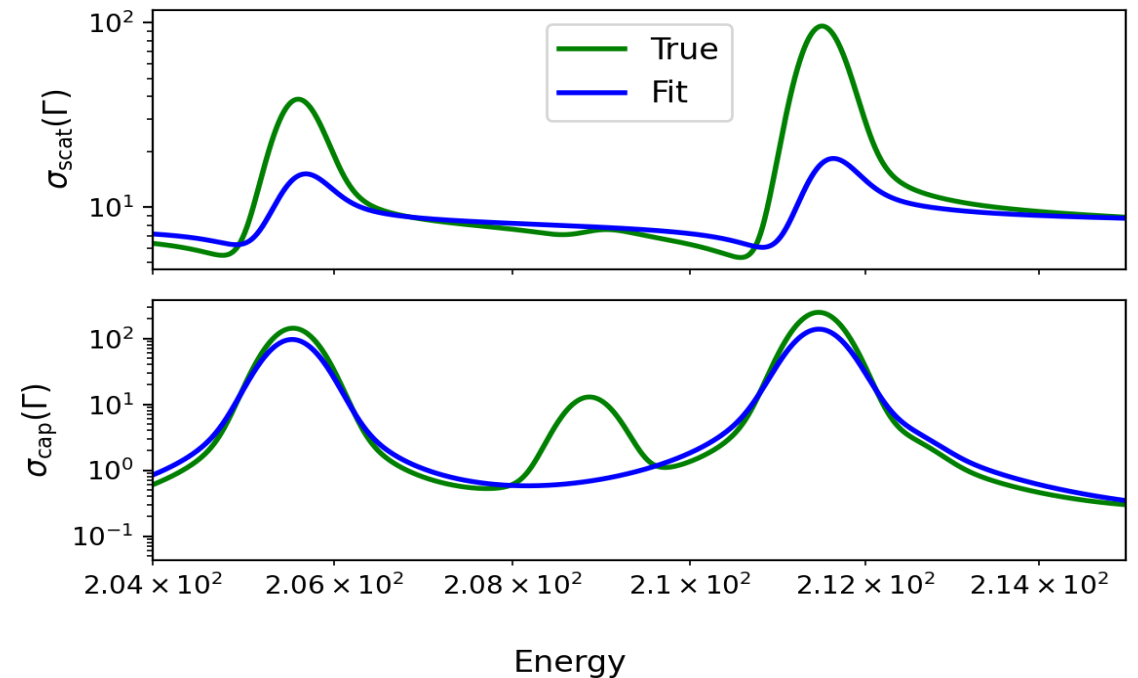
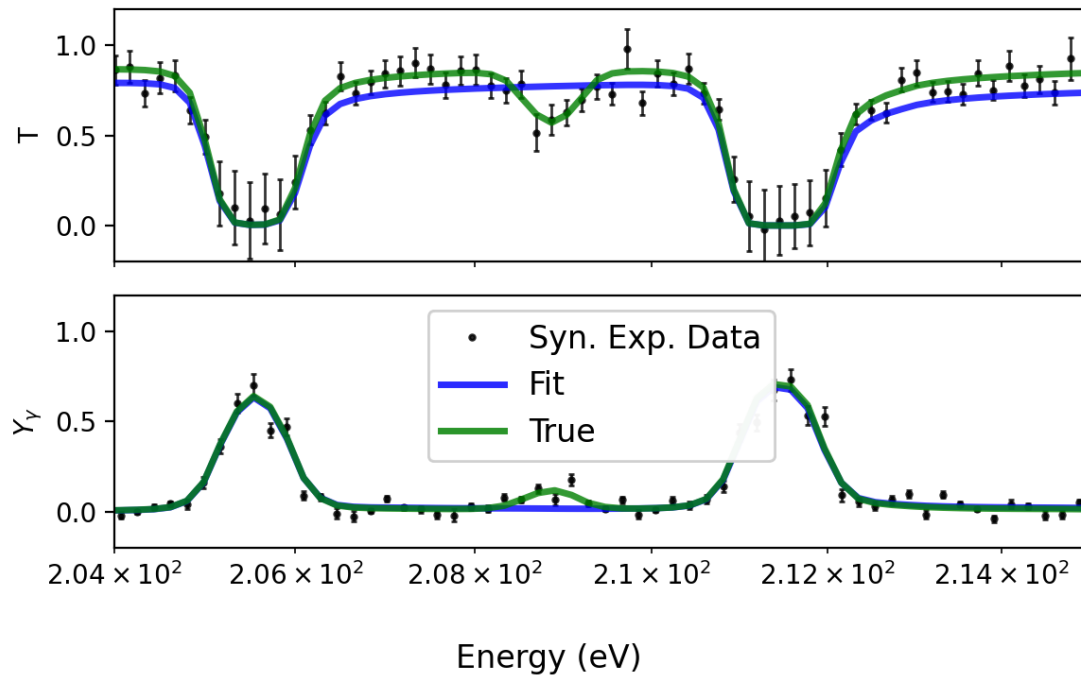
Automated, deterministic, repeatable

χ^2 fitting on par with human evaluators

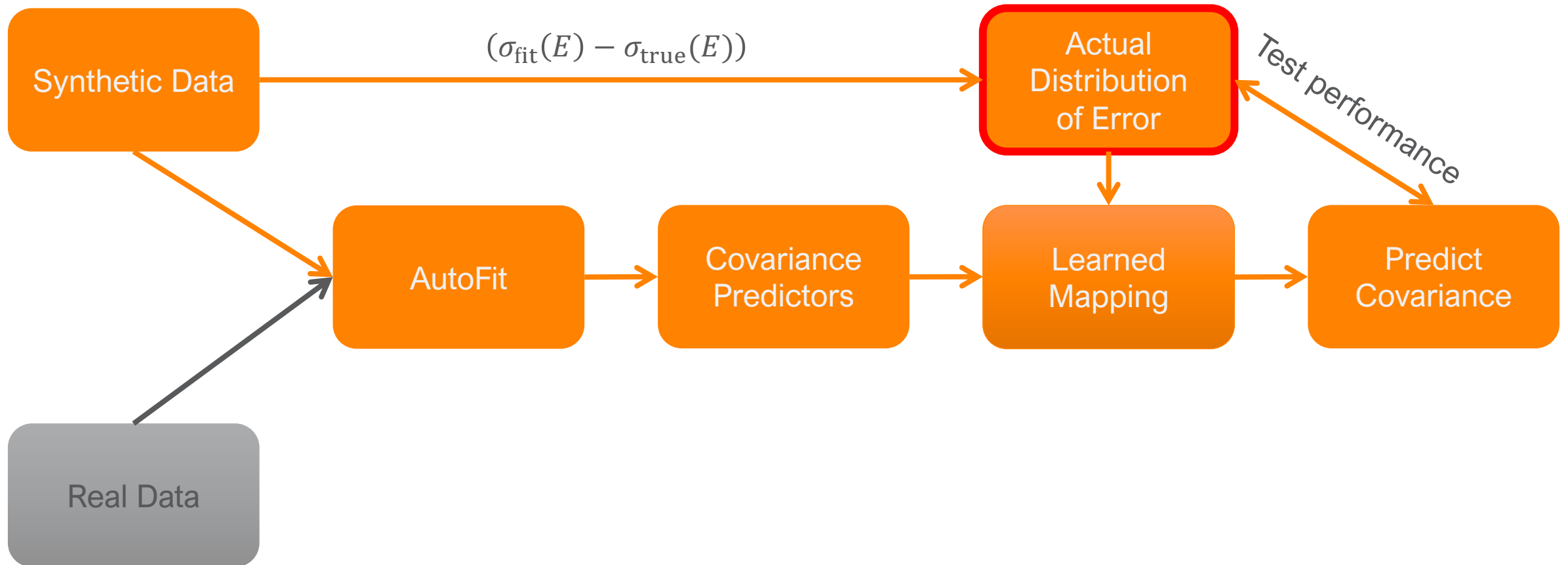


Why Synthetic Data?

- A repeatable test environment with **ground truth**
- “Best Case” scenario: all **Unknown Sources of Uncertainty** can be controlled
- Reveals the **true distribution of errors**



Approach Overview

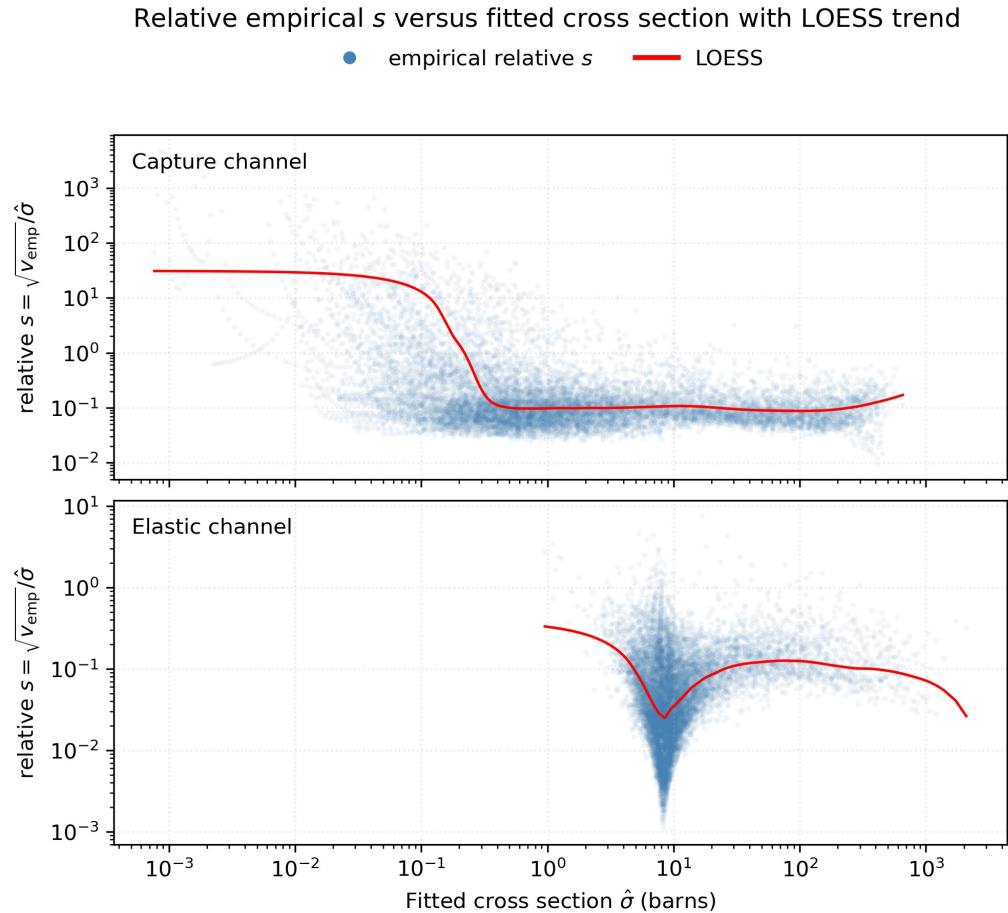


What Synthetic Data Tests Reveal

- 500,000 cross section fits
- 3 transmission data sets
- 2 capture yield data sets

~10% error in cross section

- Both capture and elastic
- Nearly independent of cross section value
i.e.: resonance peak or valley

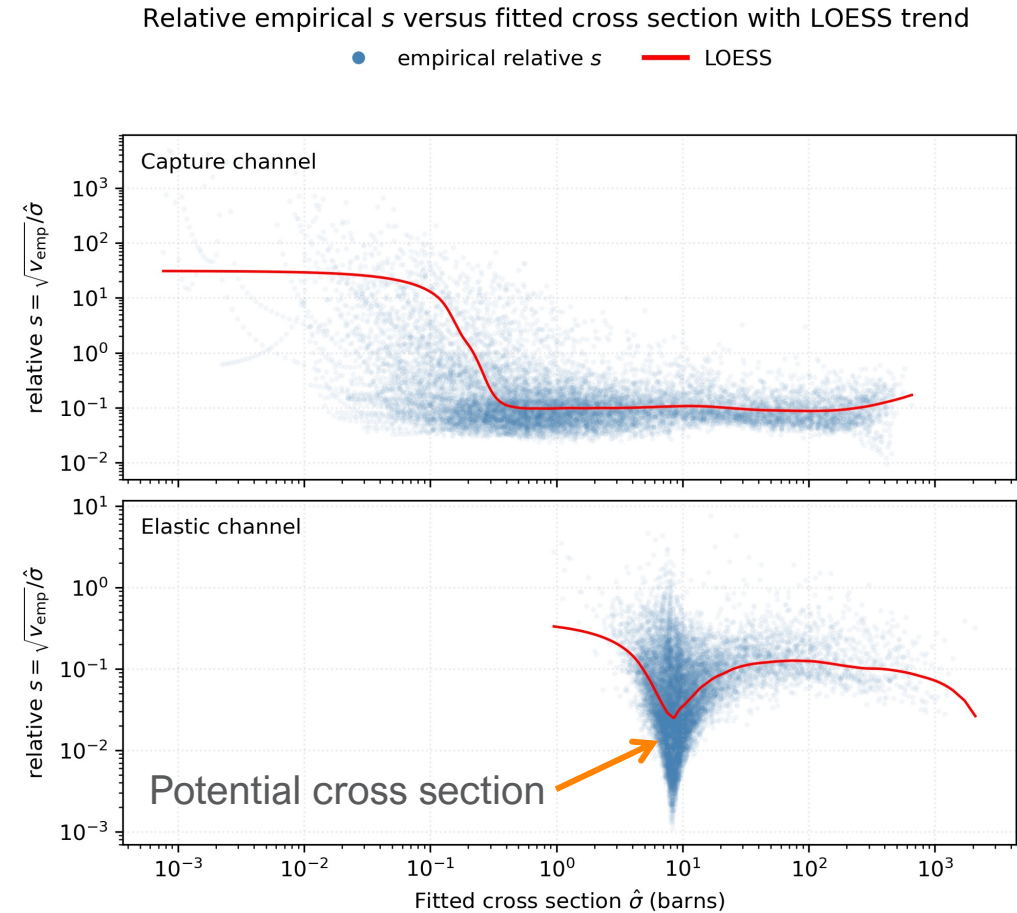


What Synthetic Data Tests Reveal

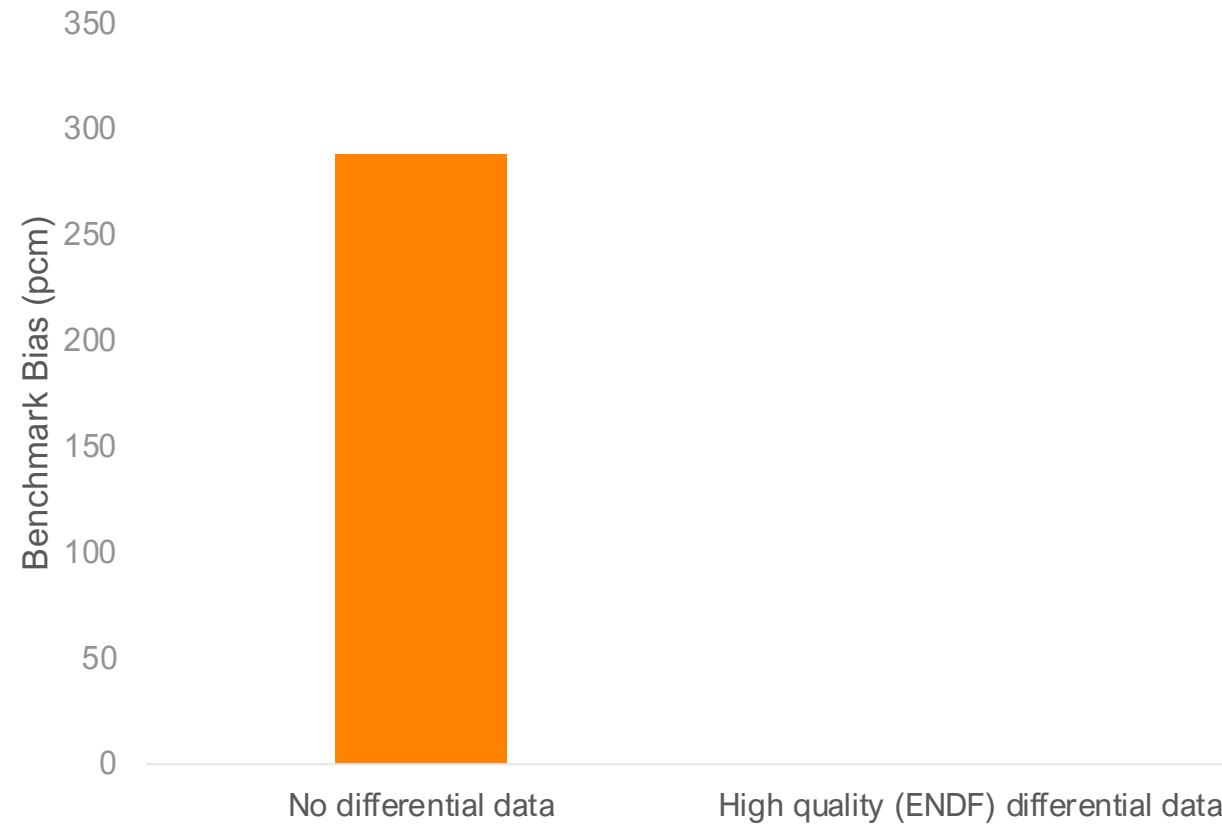
- 500,000 cross section fits
- 3 transmission data sets
- 2 capture yield data sets

~10% error in cross section

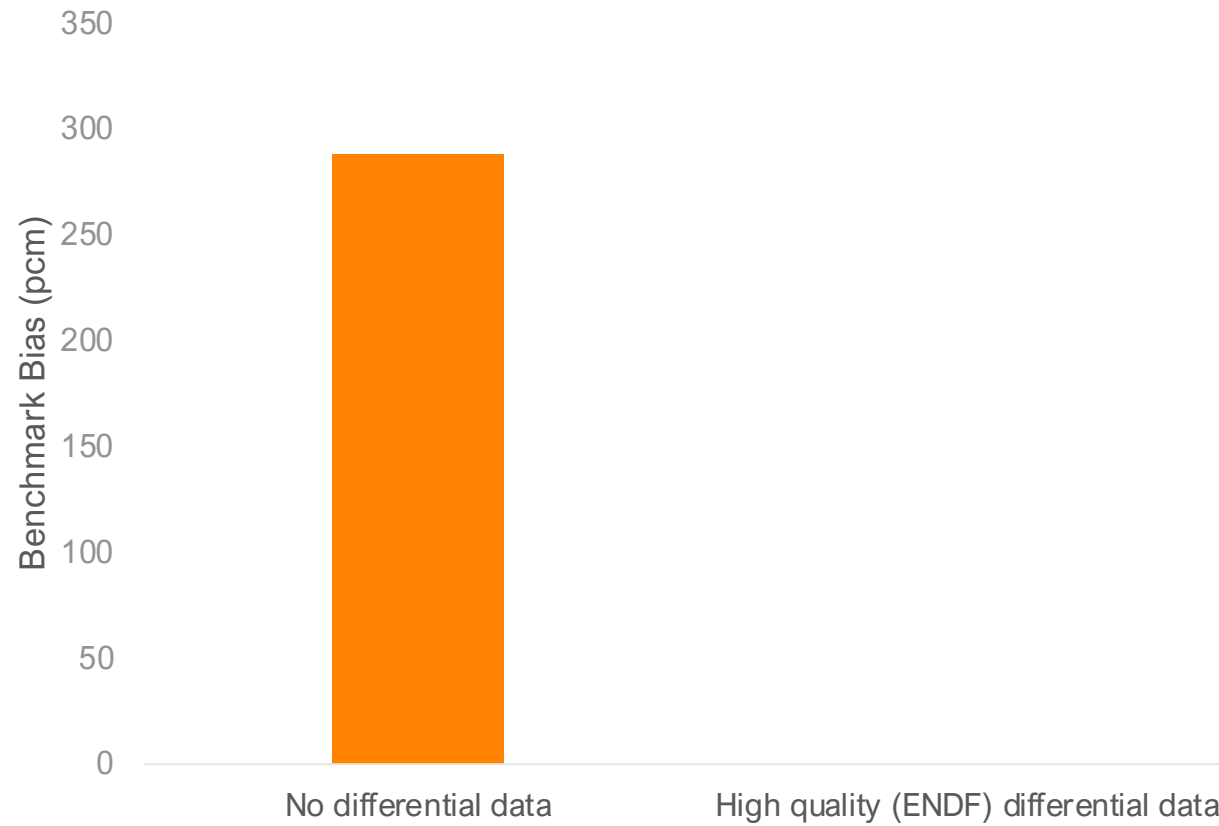
- Both capture and elastic
- Nearly independent of cross section value
i.e.: resonance peak or valley



Example Criticality benchmark



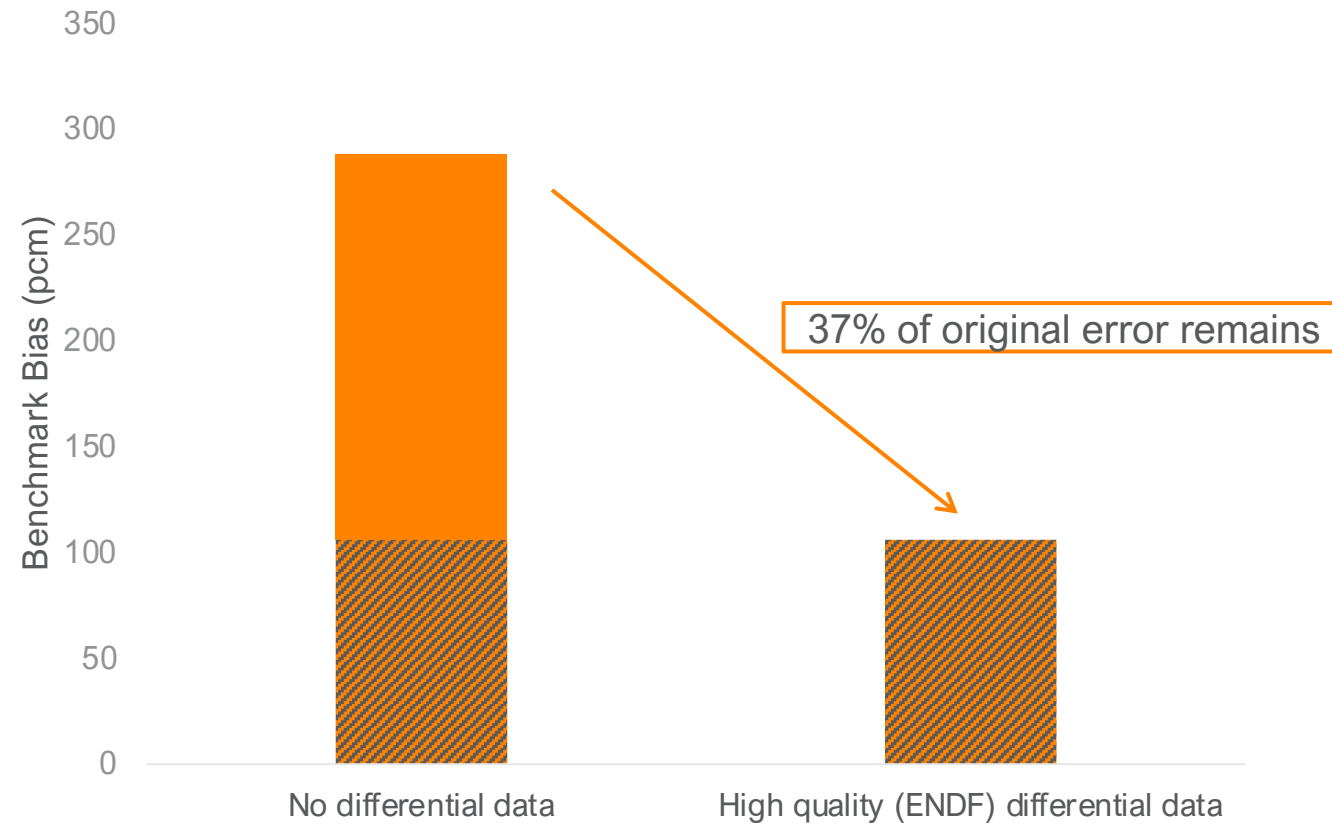
Example Criticality benchmark



“URR-like” treatment
with known average parameter values

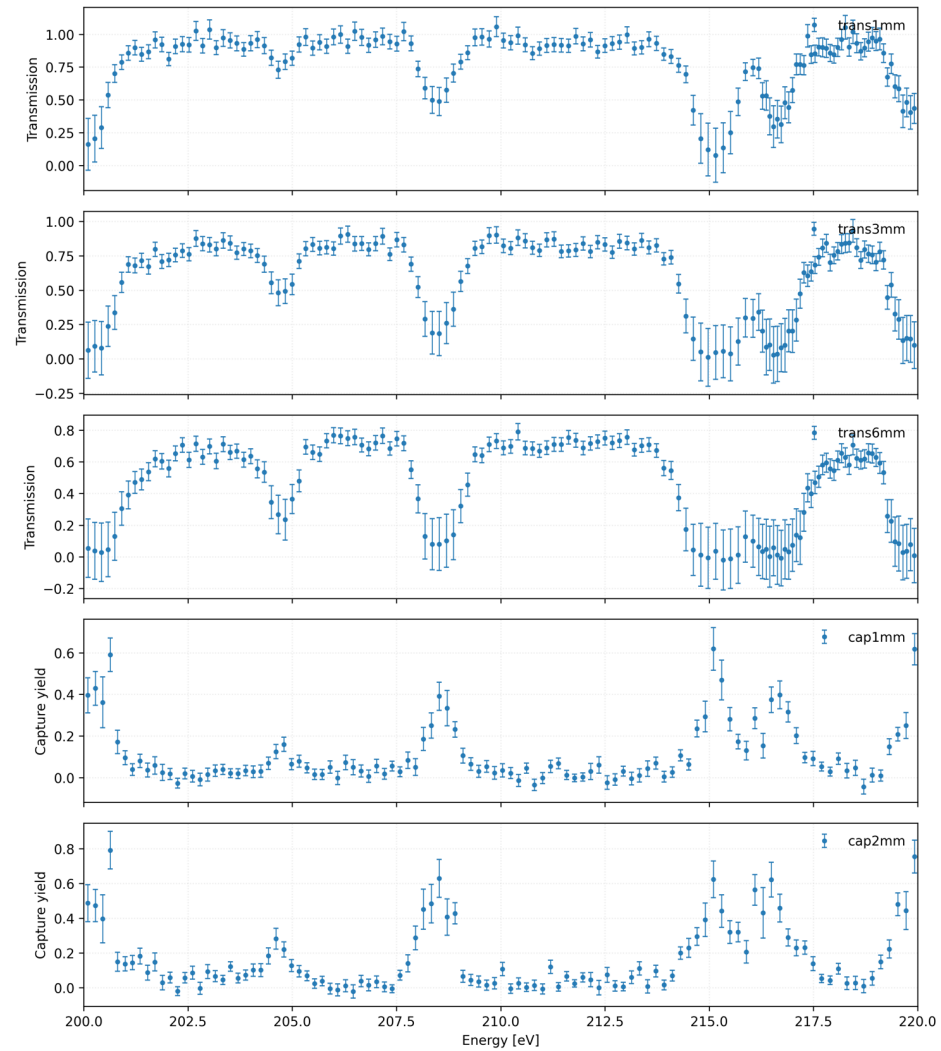


Example Criticality benchmark

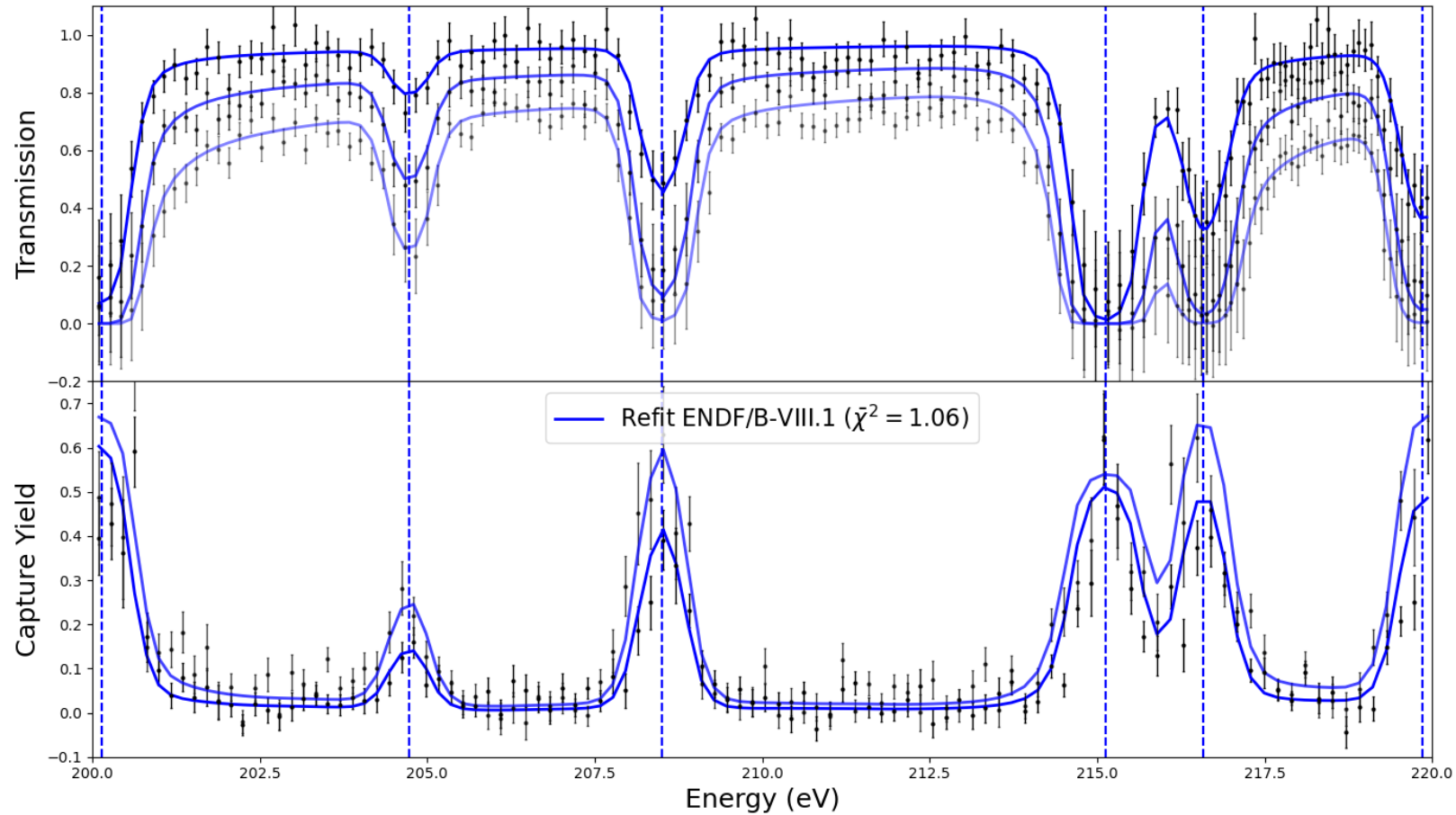


Transition to Real Data

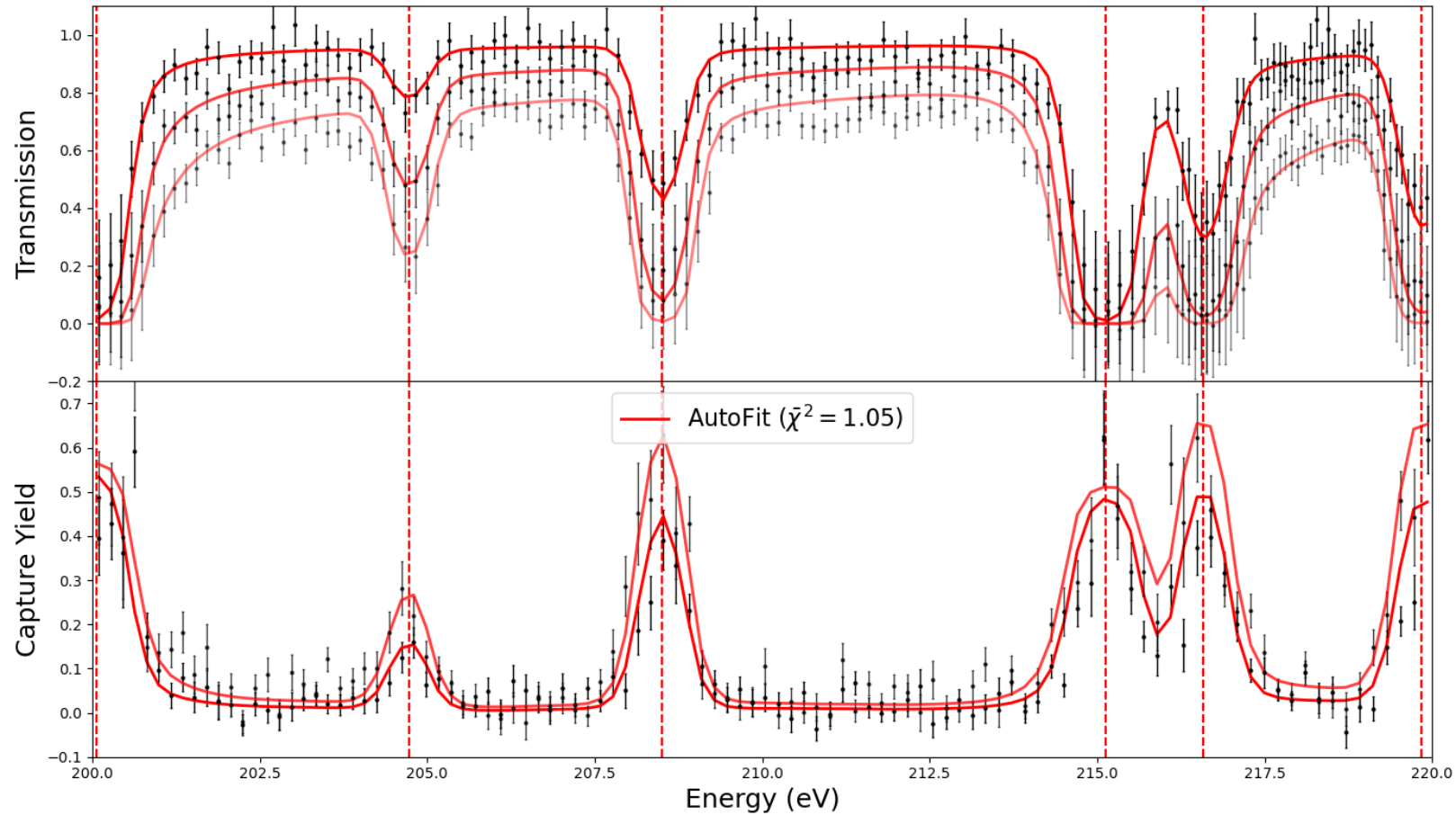
Real Data



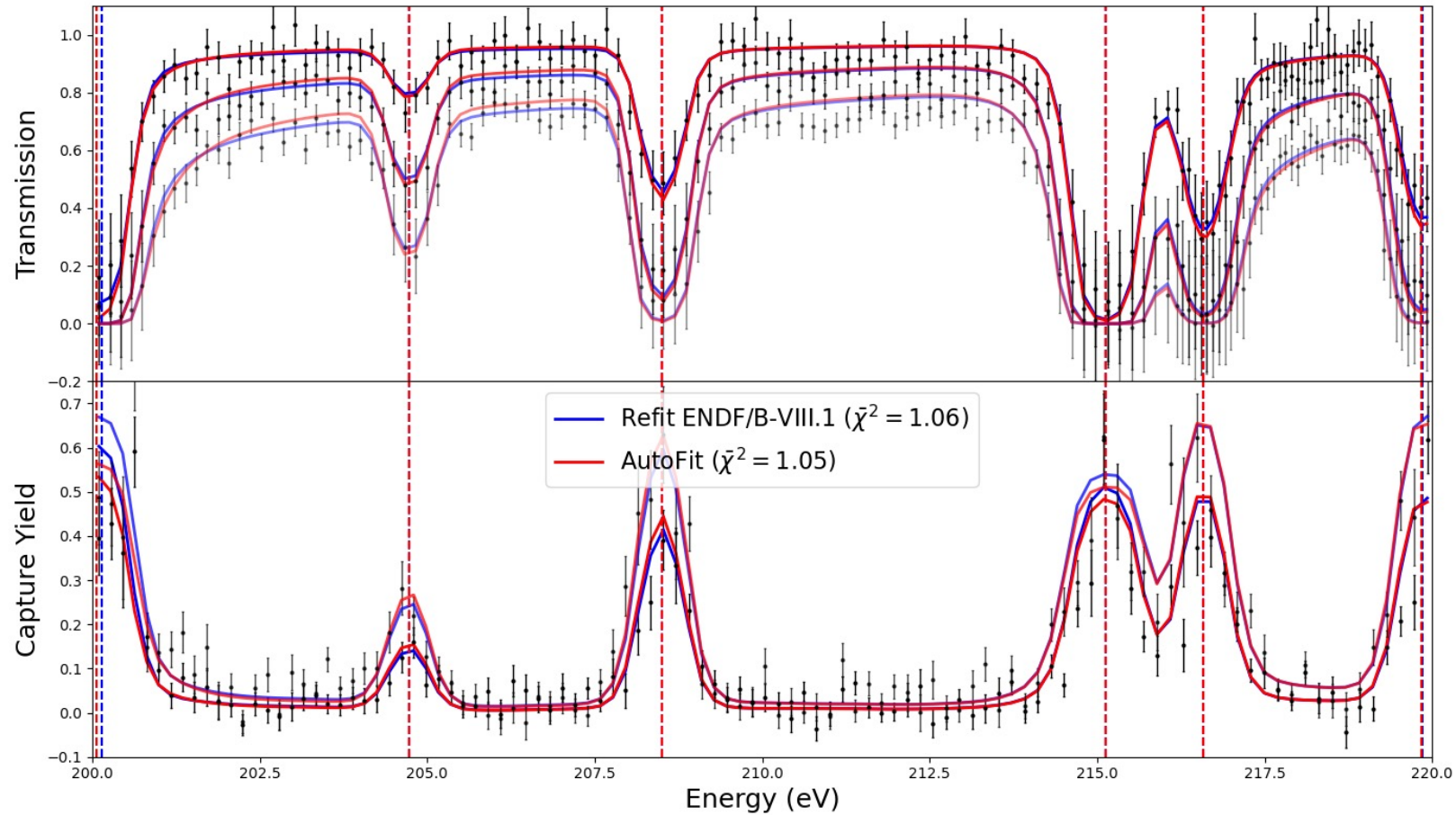
ENDF Fit



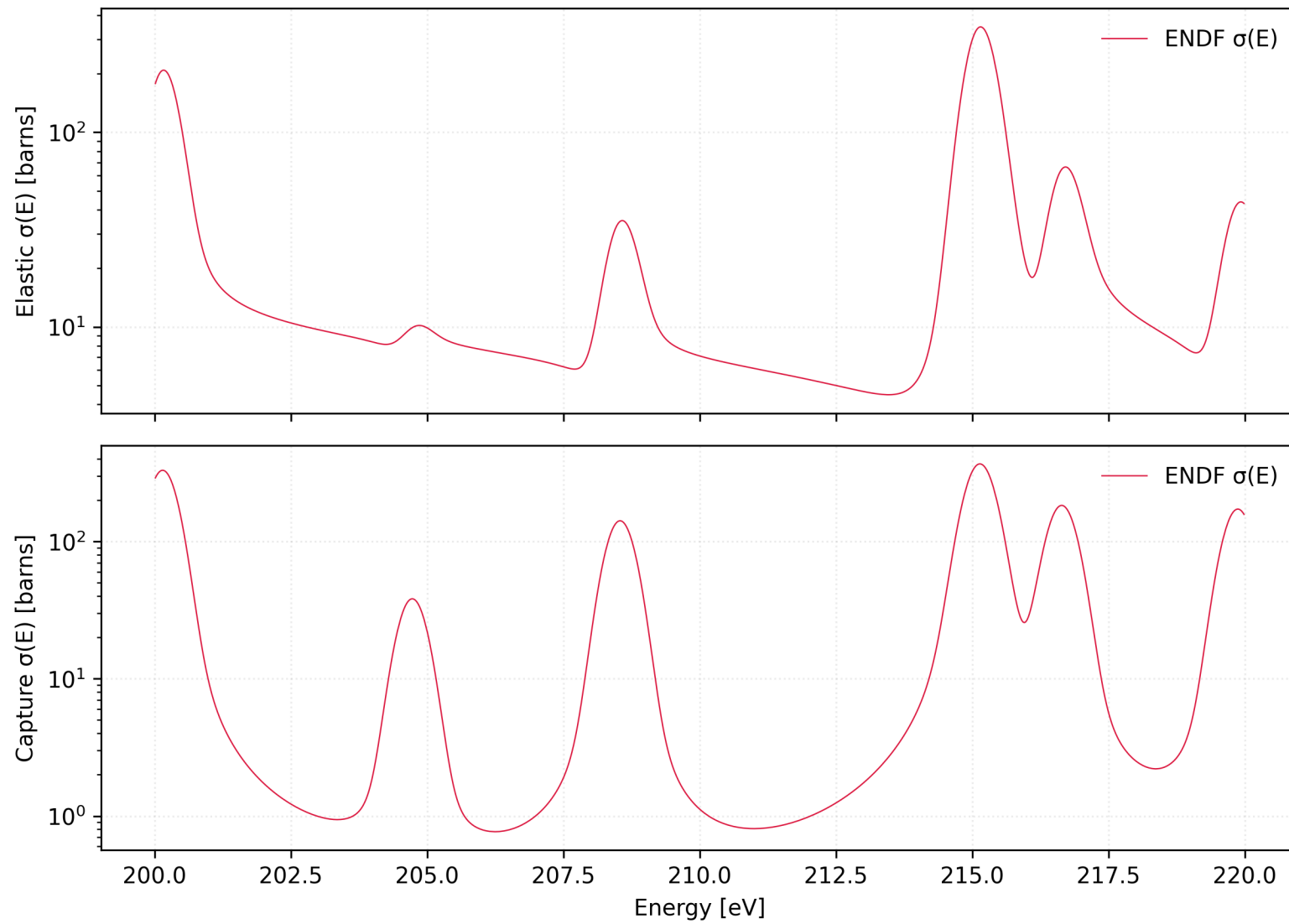
AutoFit



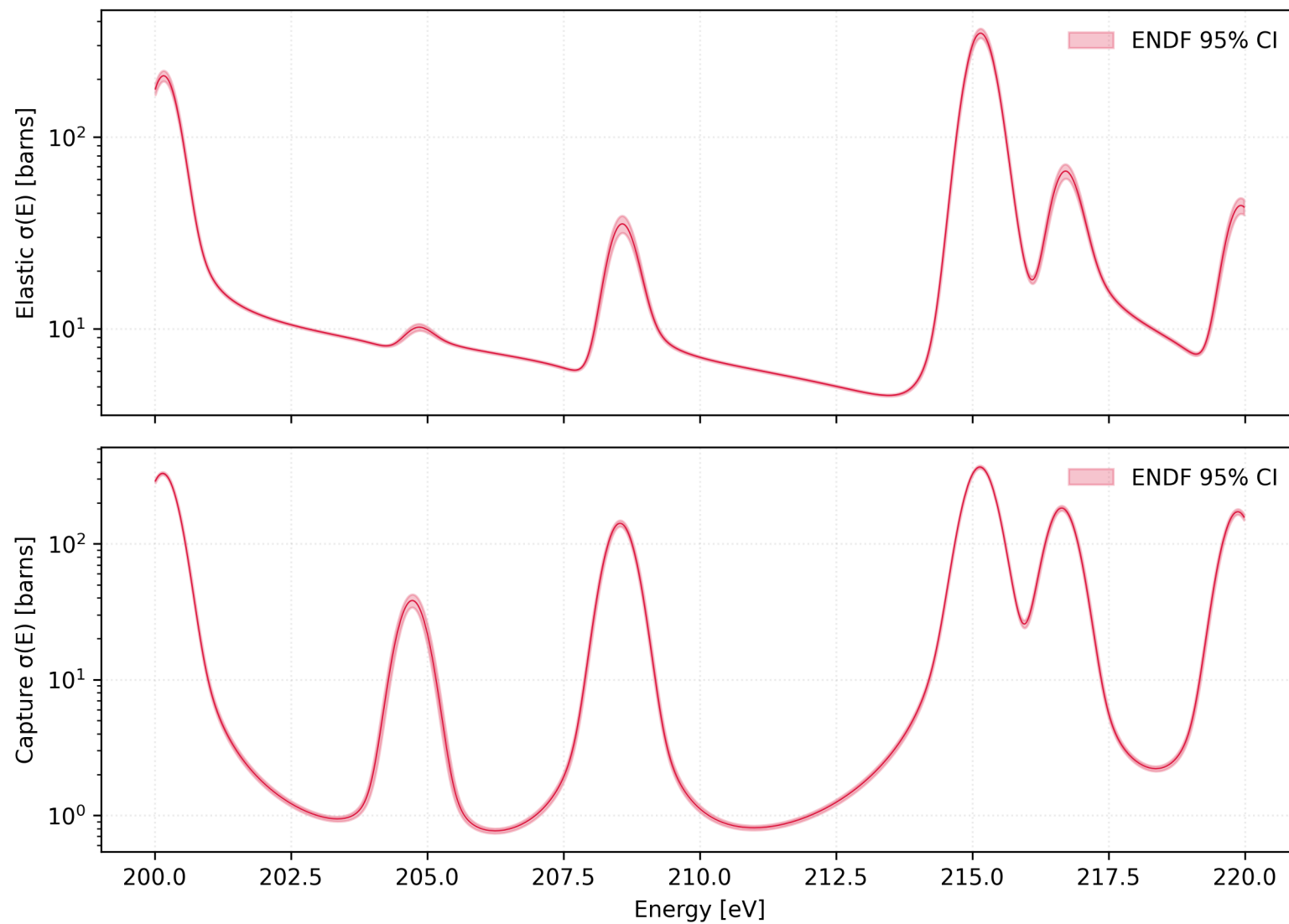
Fit Comparison



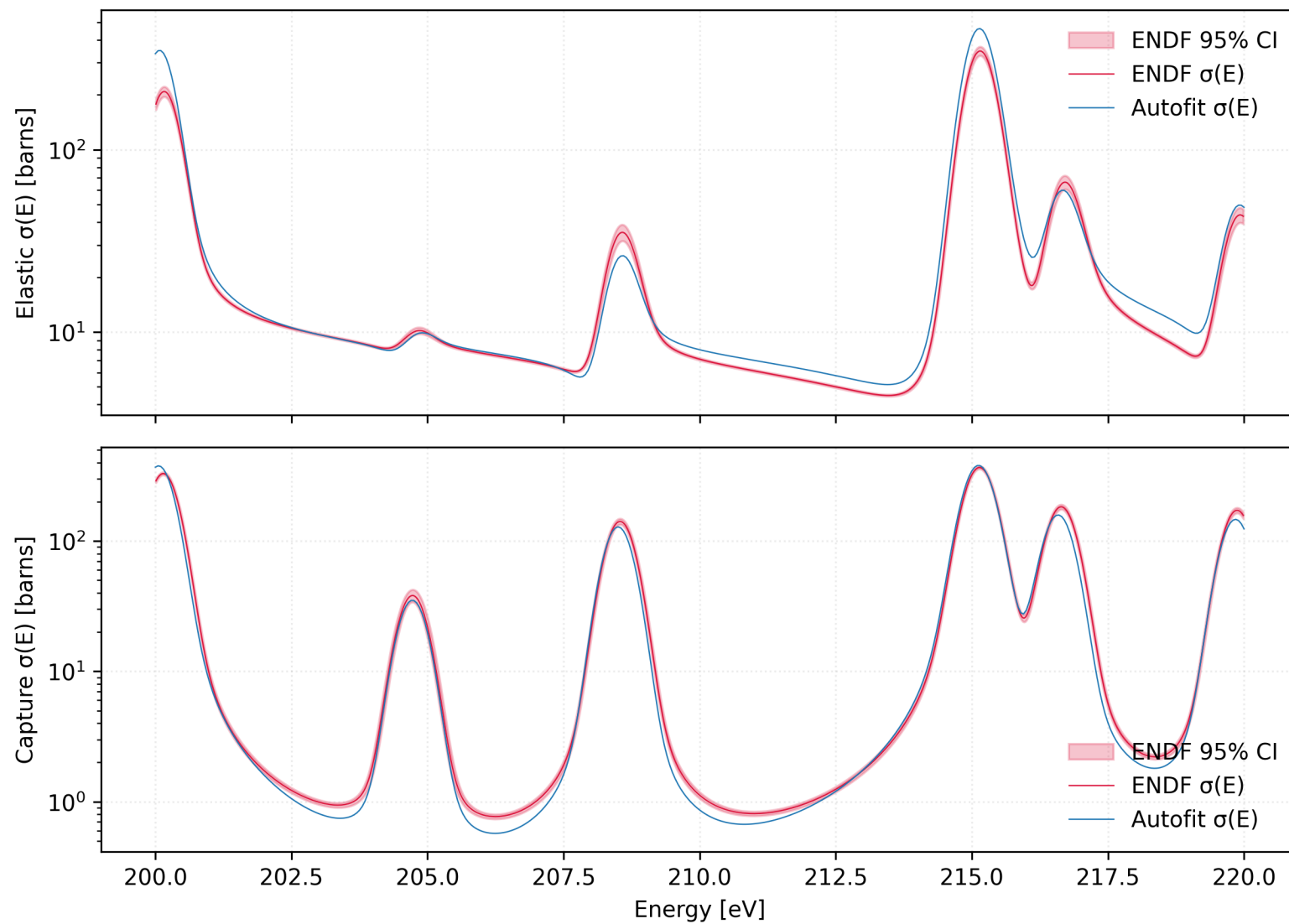
ENDF Cross Section



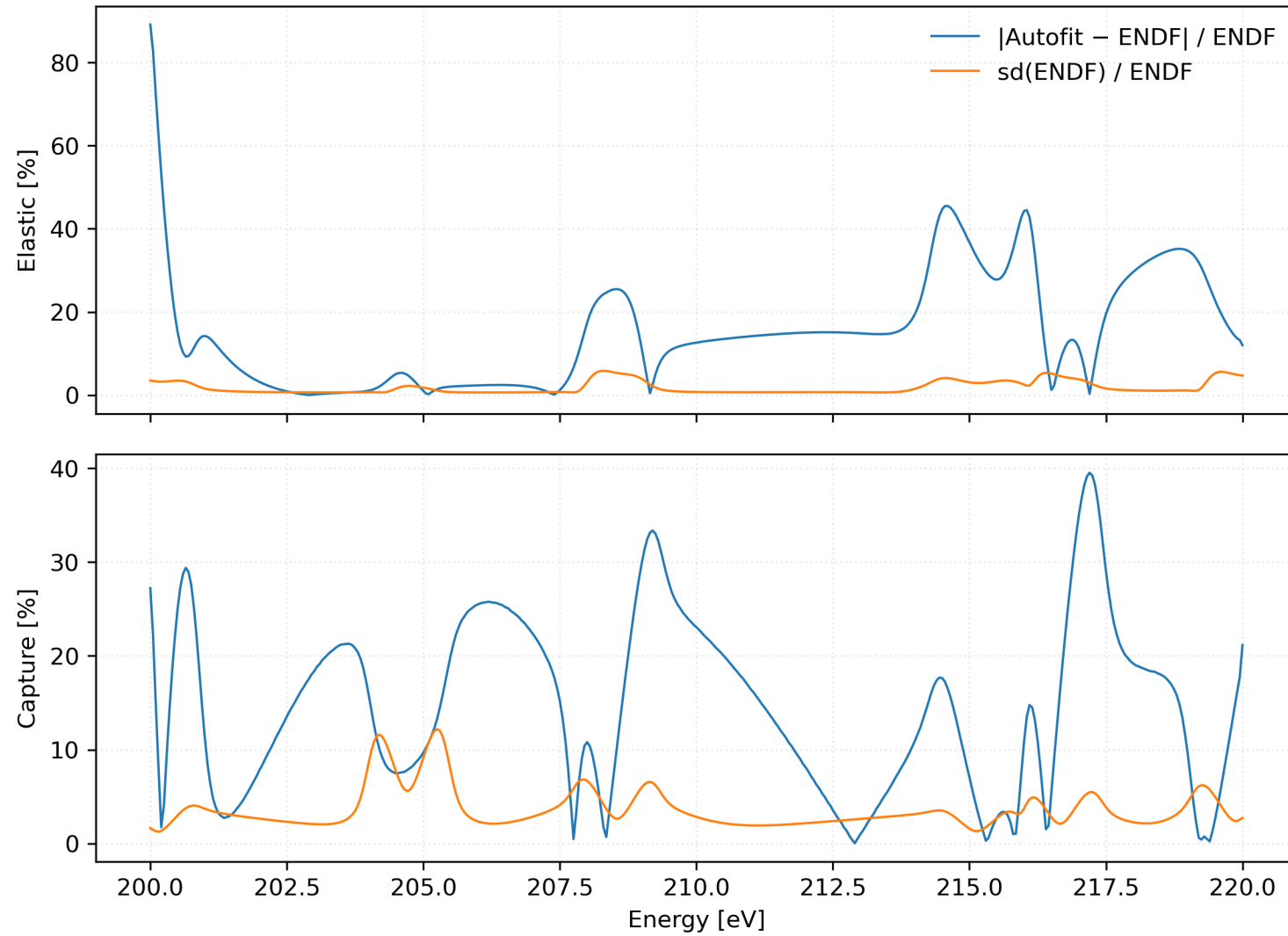
ENDF Confidence Intervals



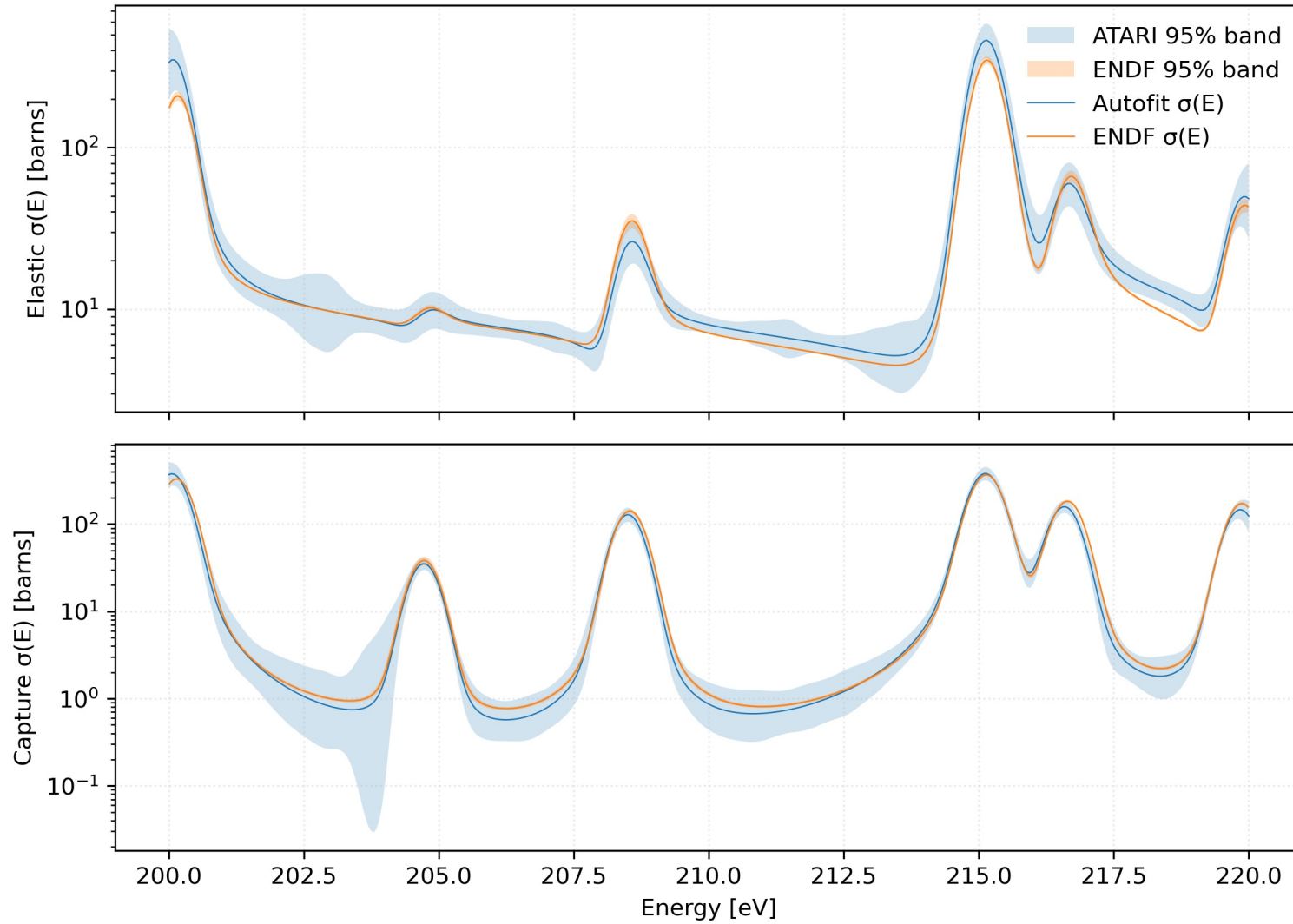
Confidence Intervals vs. Alternate Fit



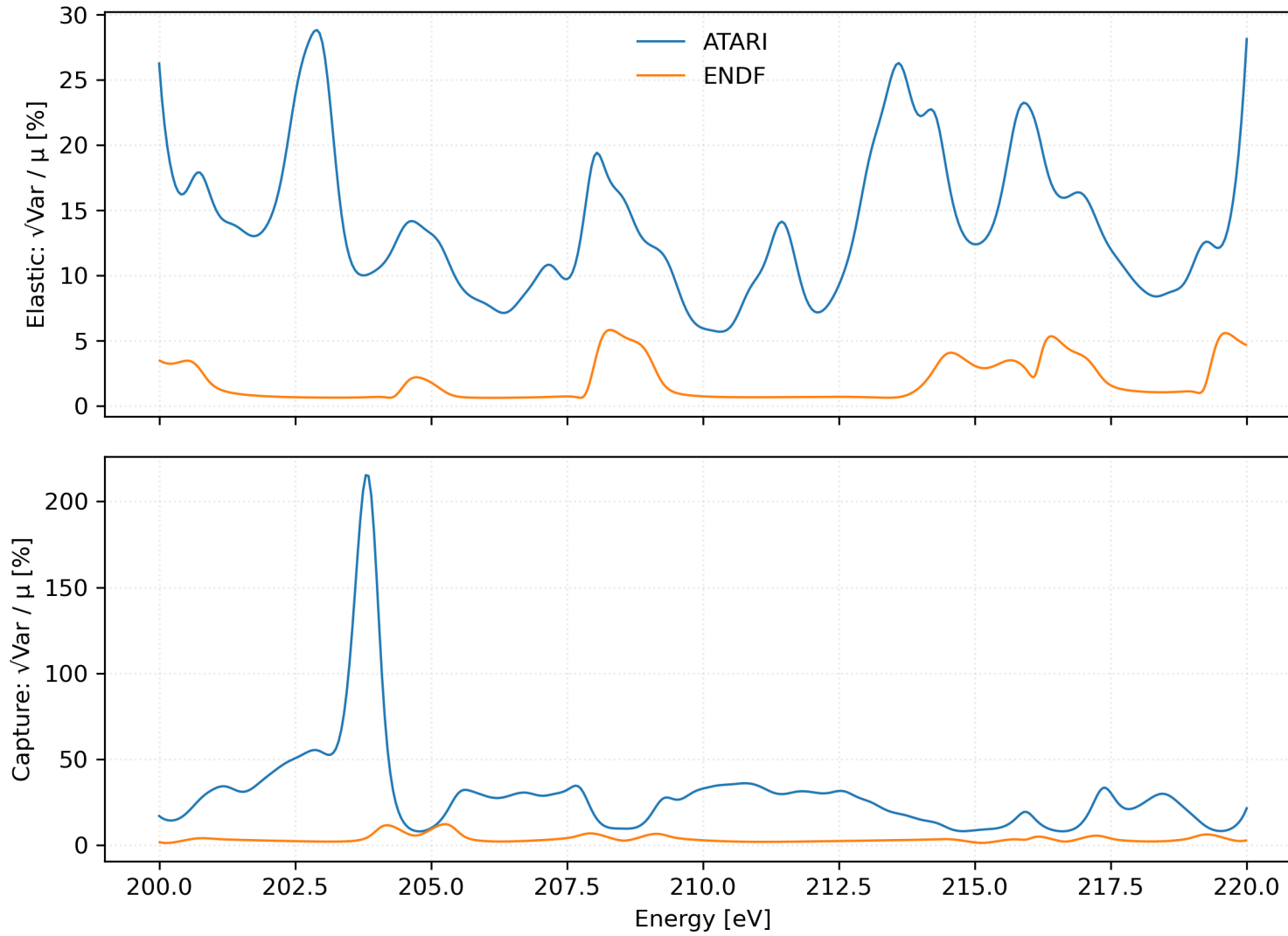
Confidence Intervals vs Relative Difference



AutoFit Confidence Intervals



AutoFit Confidence Intervals

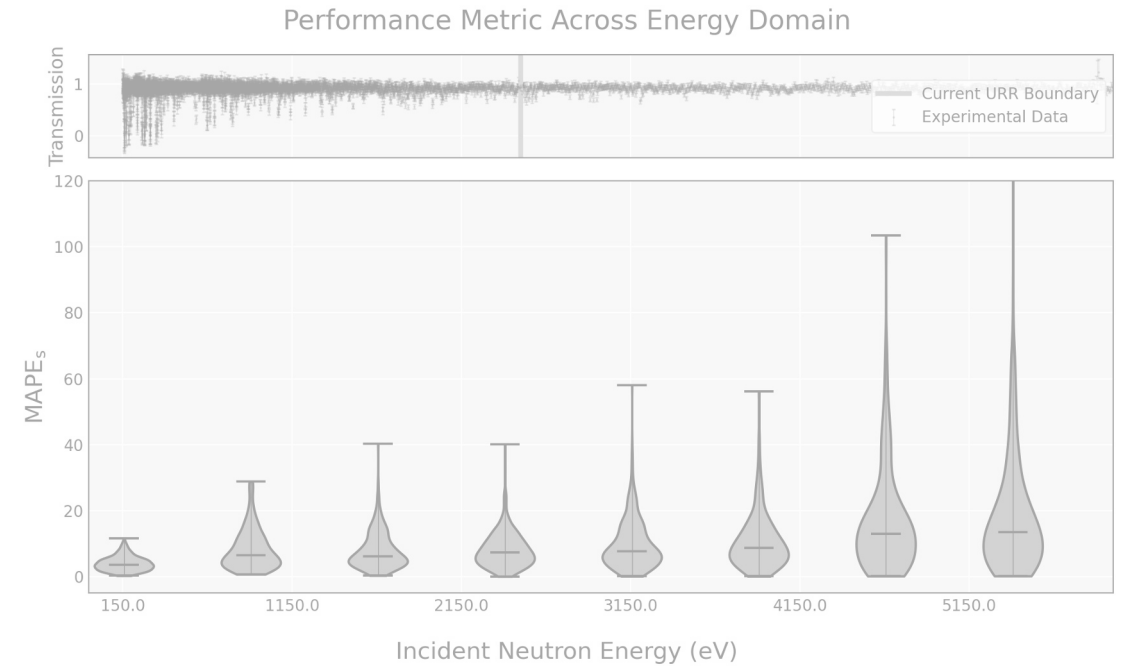


Summary

1. Can estimate the actual cross section inference uncertainty using high-fidelity synthetic data
2. Can (ML-) learn to predict cross section inference uncertainty reliably
3. Log-normal distribution of error performs best in quantitative testing

Future work

- Expand to full RRR (current test at low-energy)
- Explore other error distributions
- Demonstrate impact of updated uncertainty evaluation on benchmarks/applications

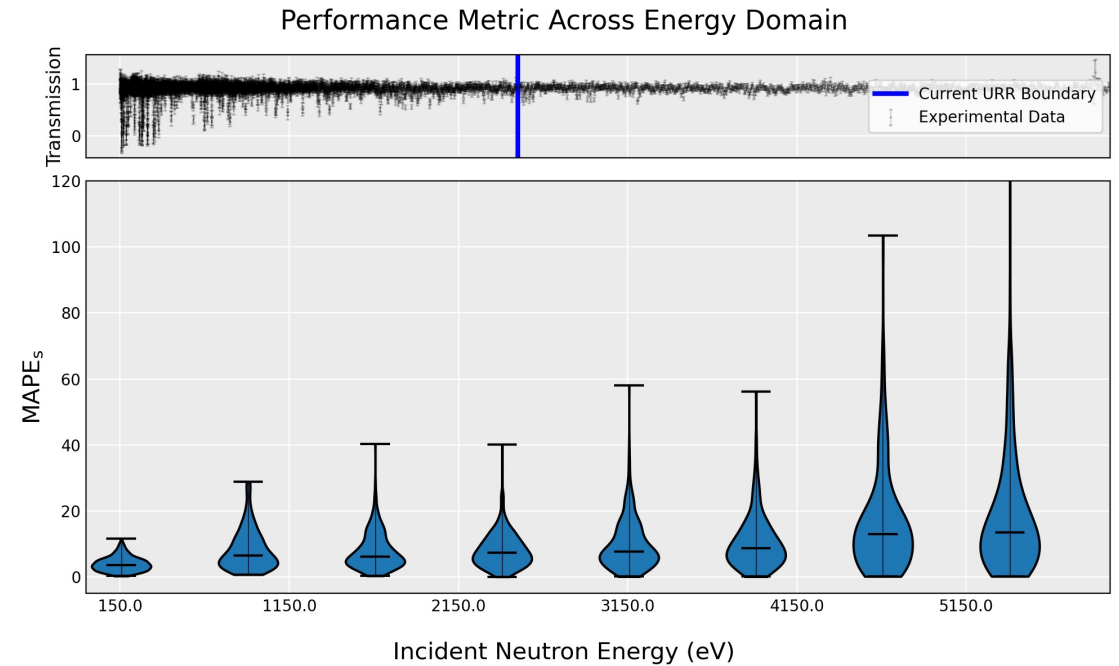


Summary

1. Can estimate the actual cross section inference uncertainty using high-fidelity synthetic data
2. Can (ML-) learn to predict cross section inference uncertainty reliably
3. Log-normal distribution of error performs best in quantitative testing

Future work

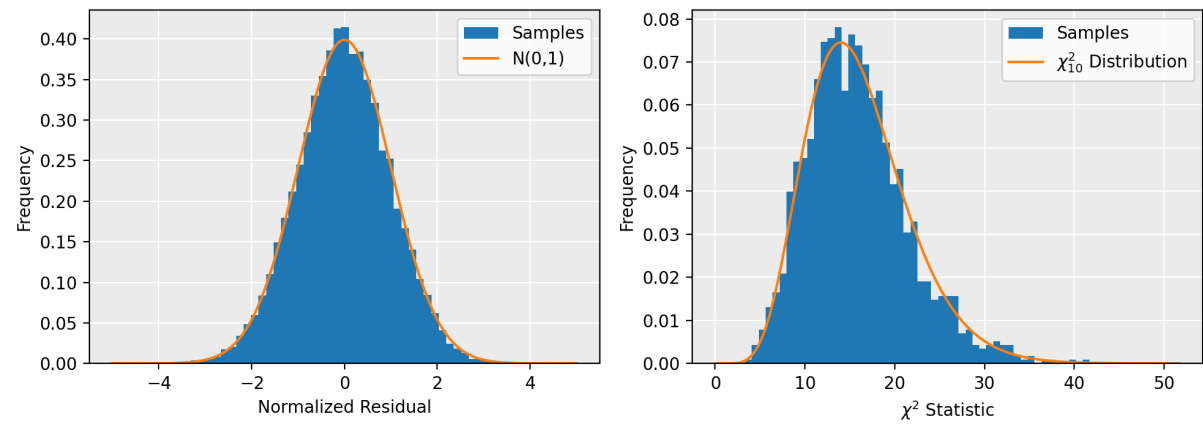
- Expand to full RRR (current test at low-energy)
- Explore other error distributions
- Demonstrate impact of updated uncertainty evaluation on benchmarks/applications



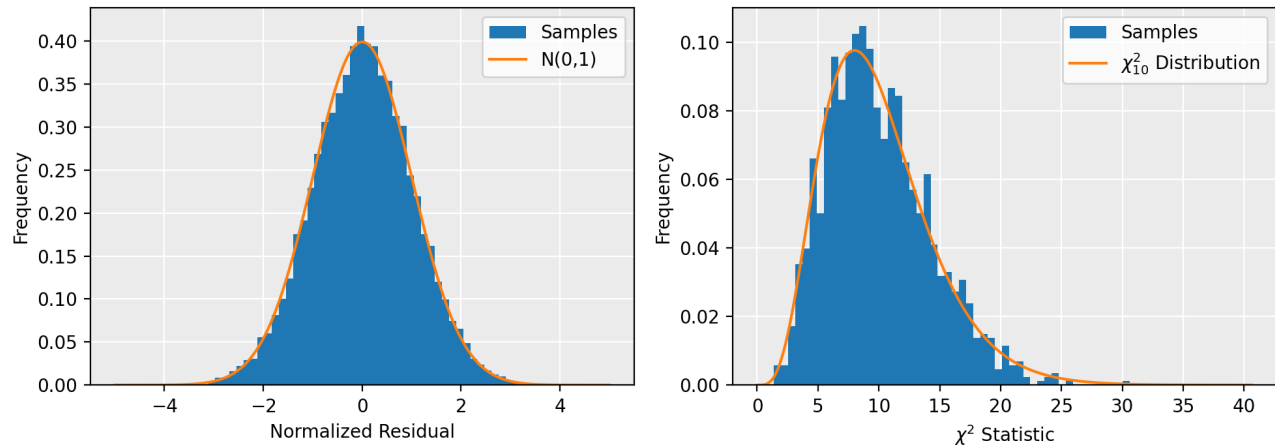
Backup Slides

Synthetic Data V & V

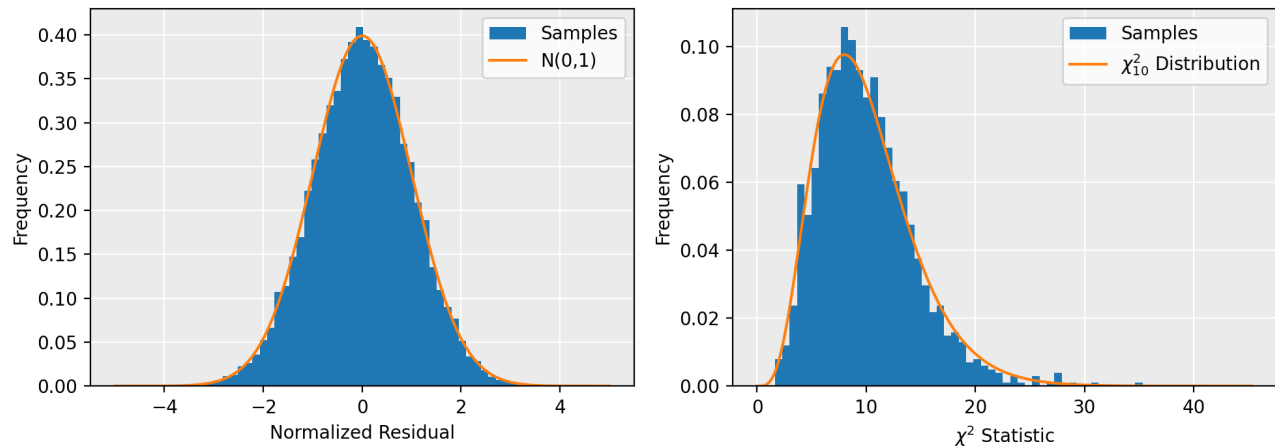
Synthetic Data Model Verification for Capture Yield

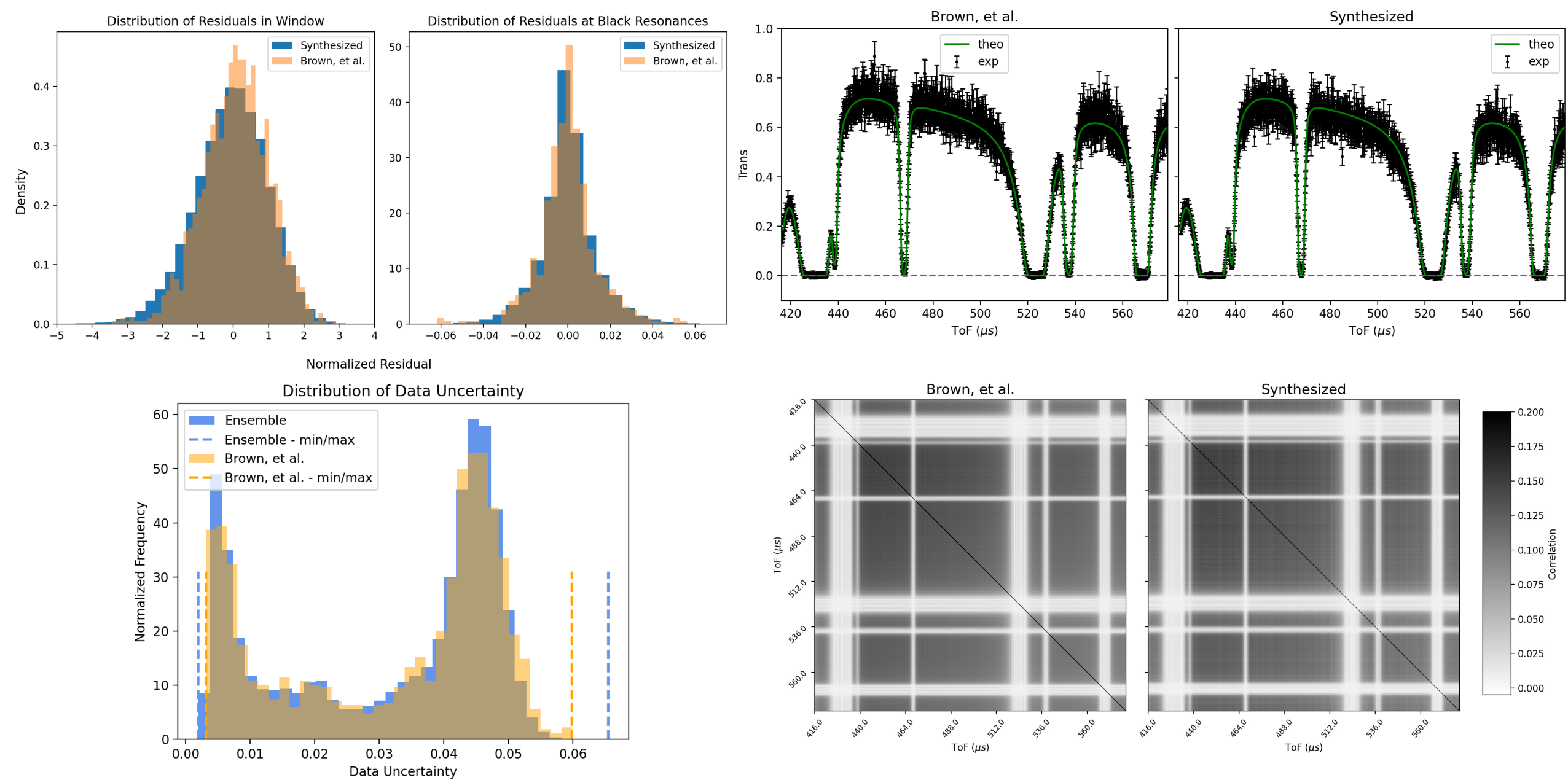


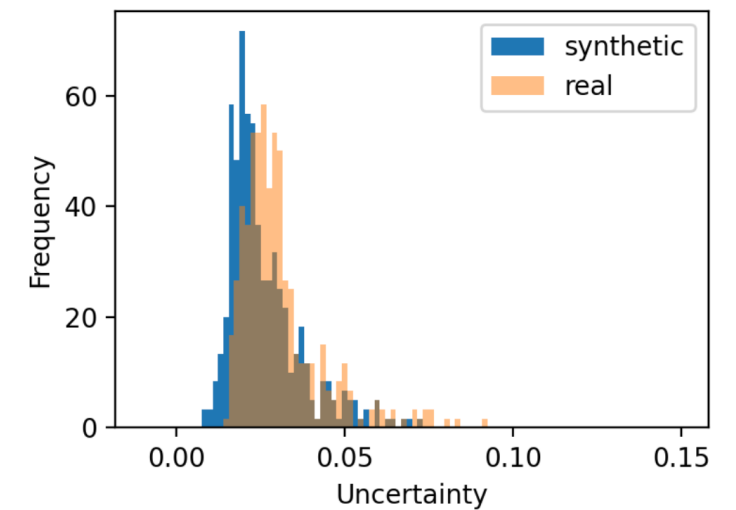
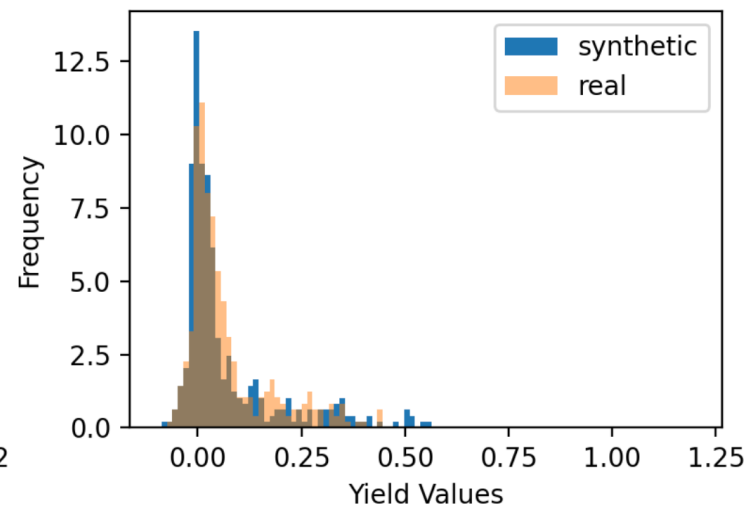
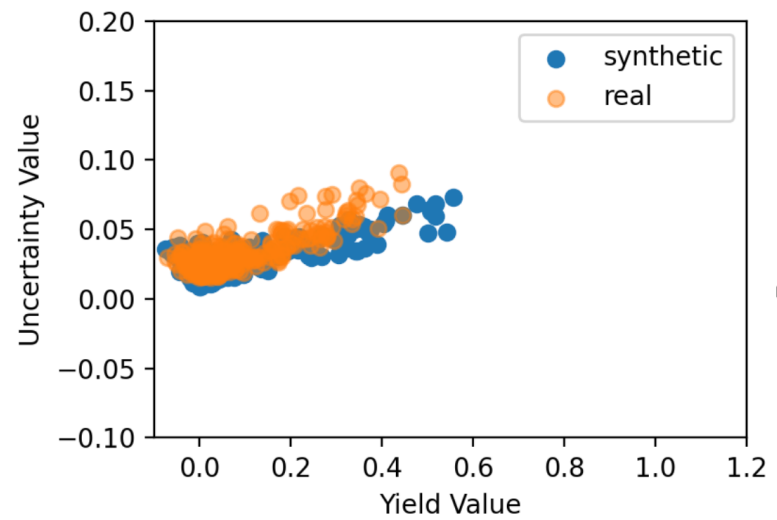
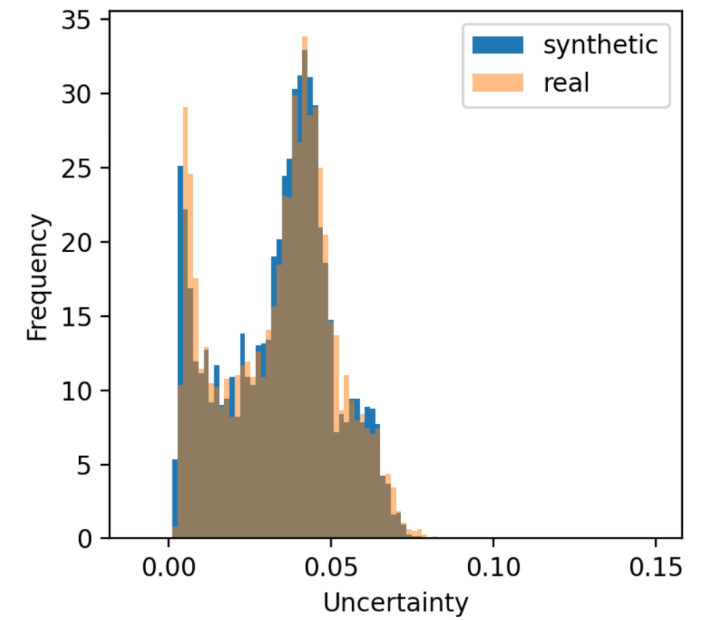
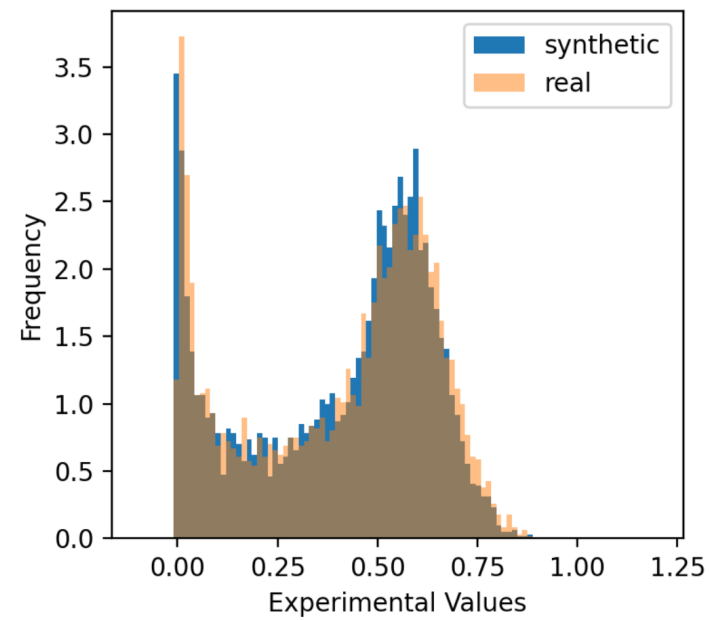
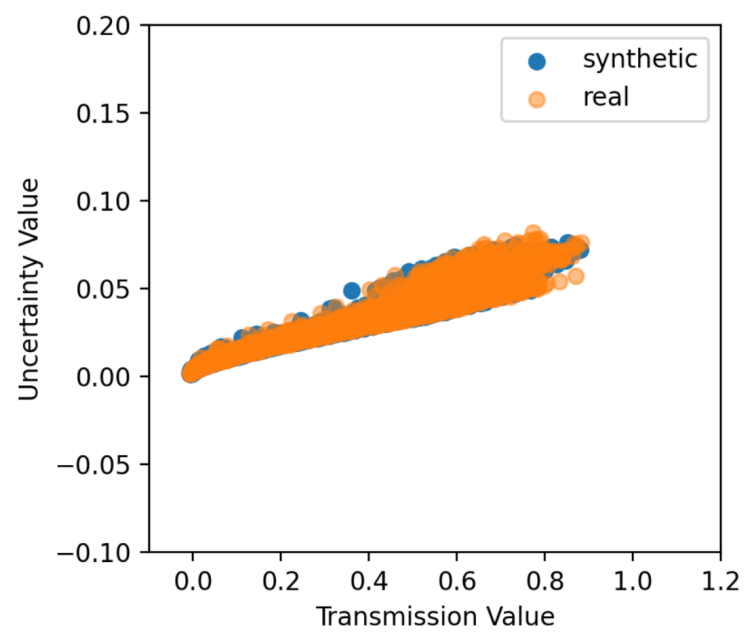
Synthetic Data Model Verification for Transmission (exponential)



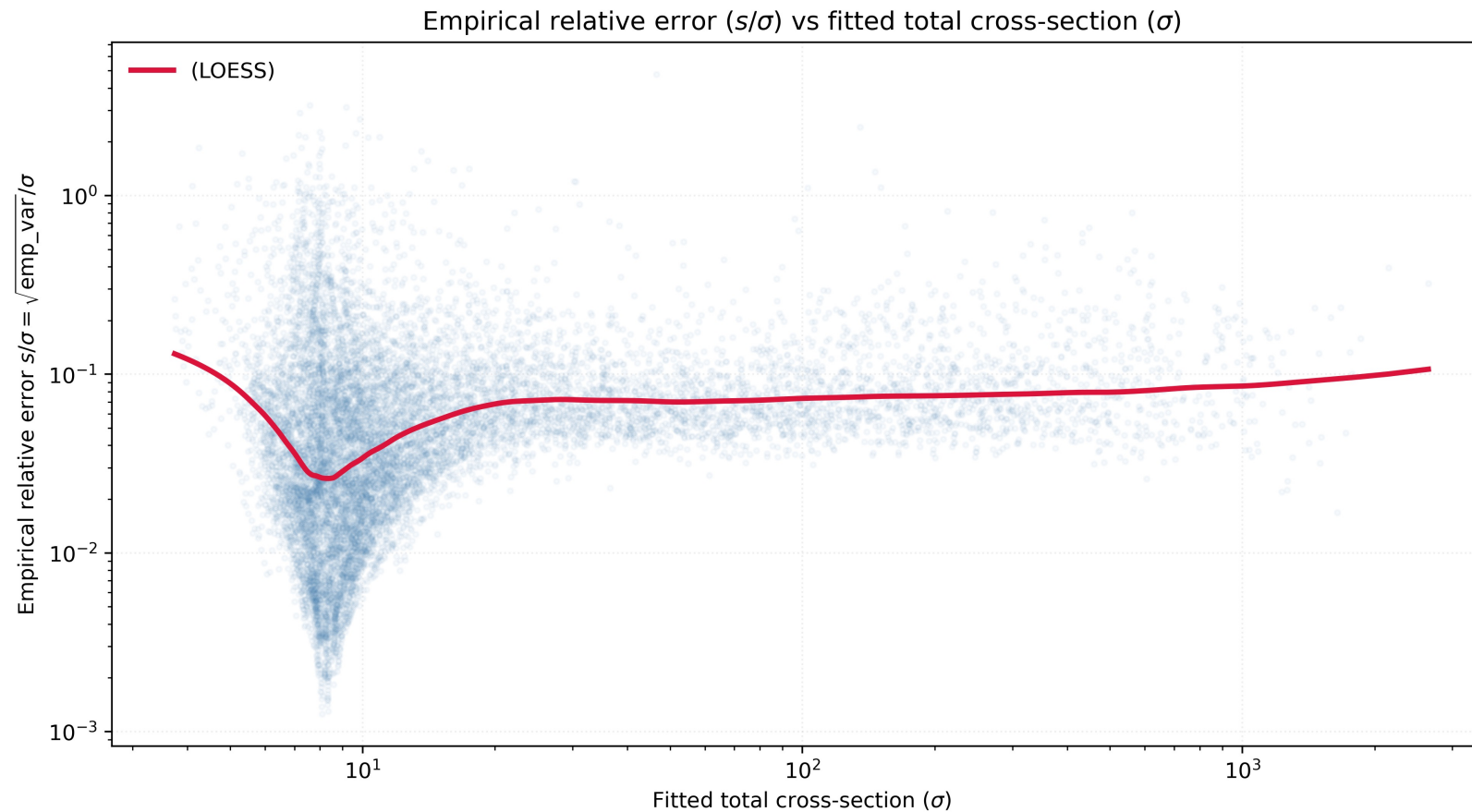
Synthetic Data Model Verification for Transmission (power)



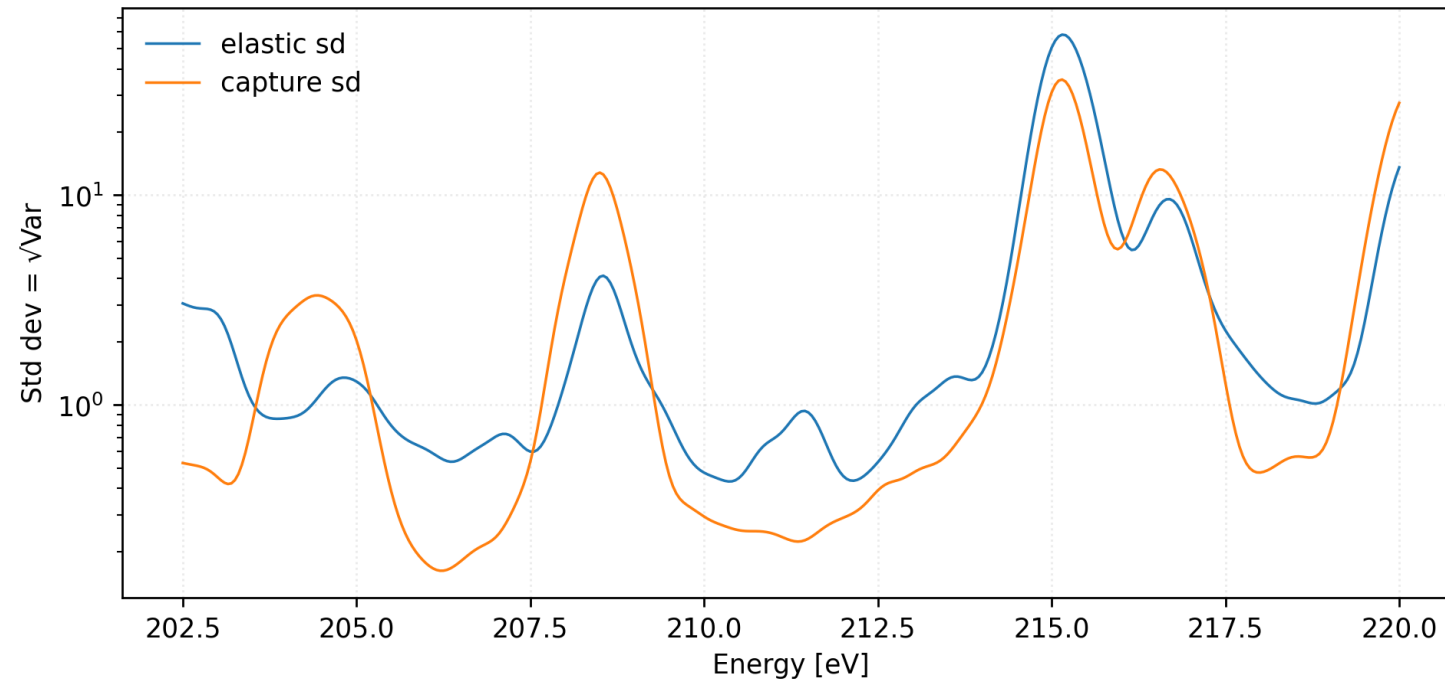




Total Cross Section Error

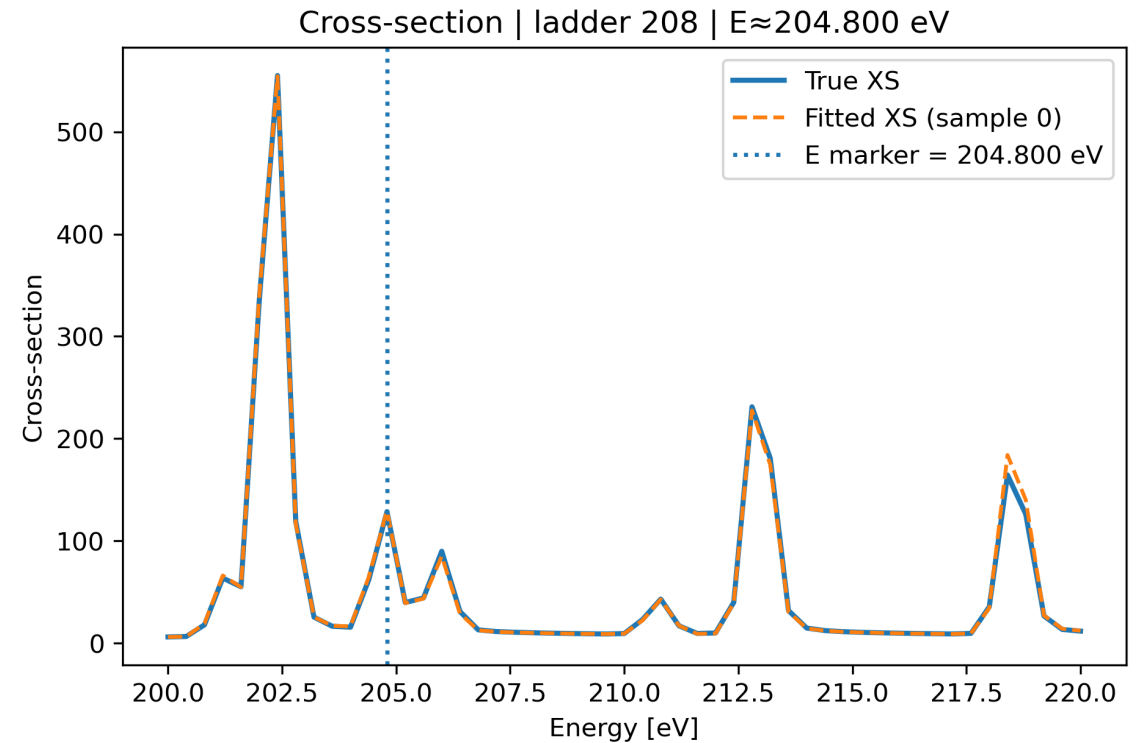
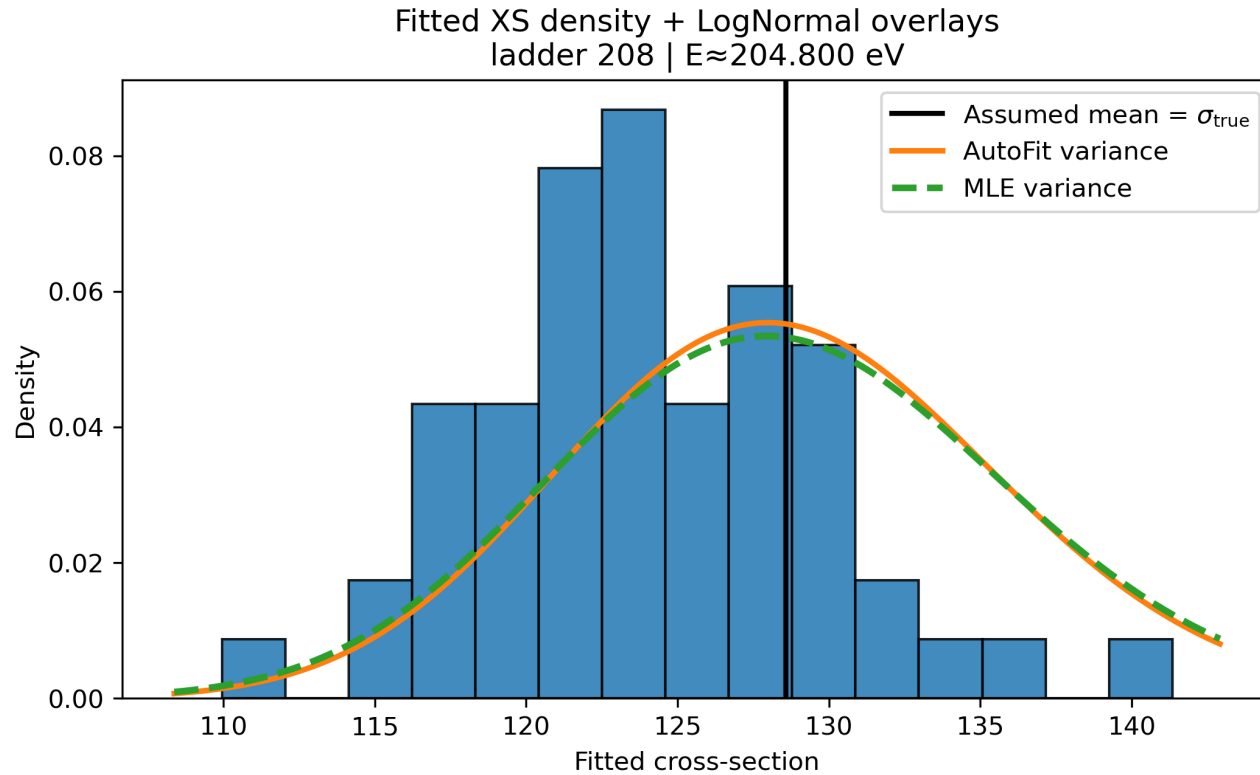


AutoFit Reaction Relative Error



Distribution of Error

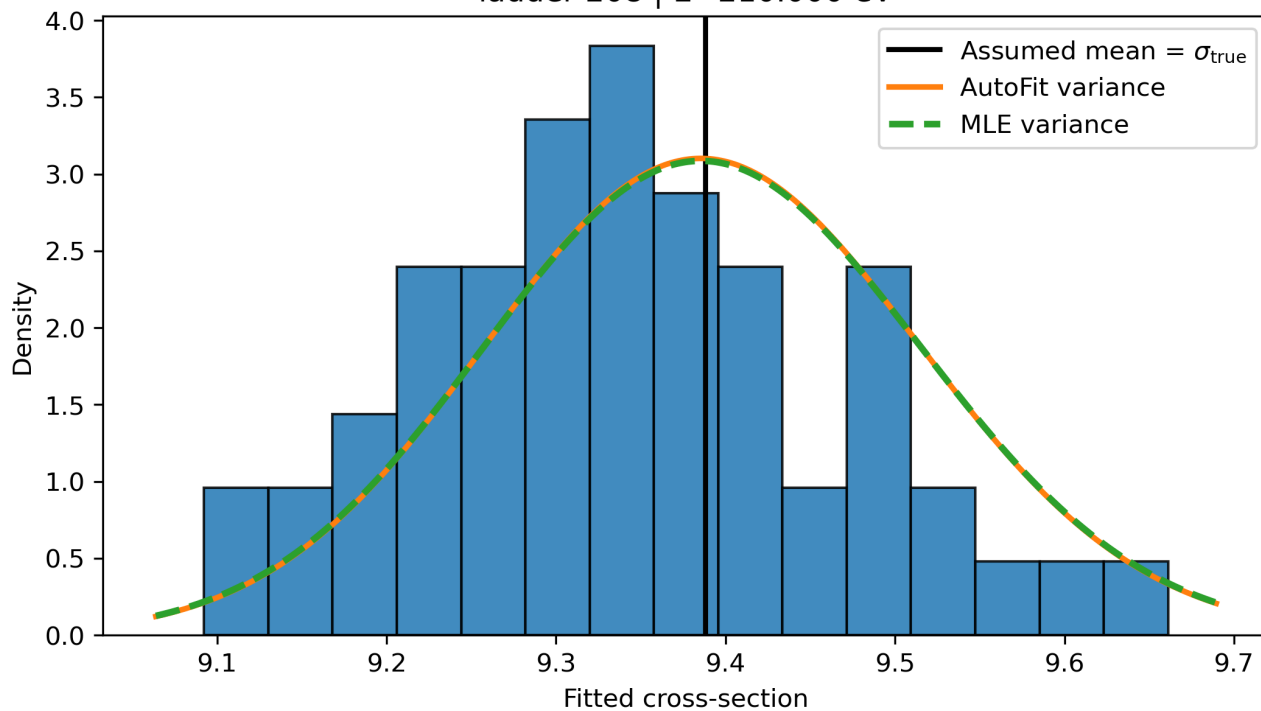
Examples



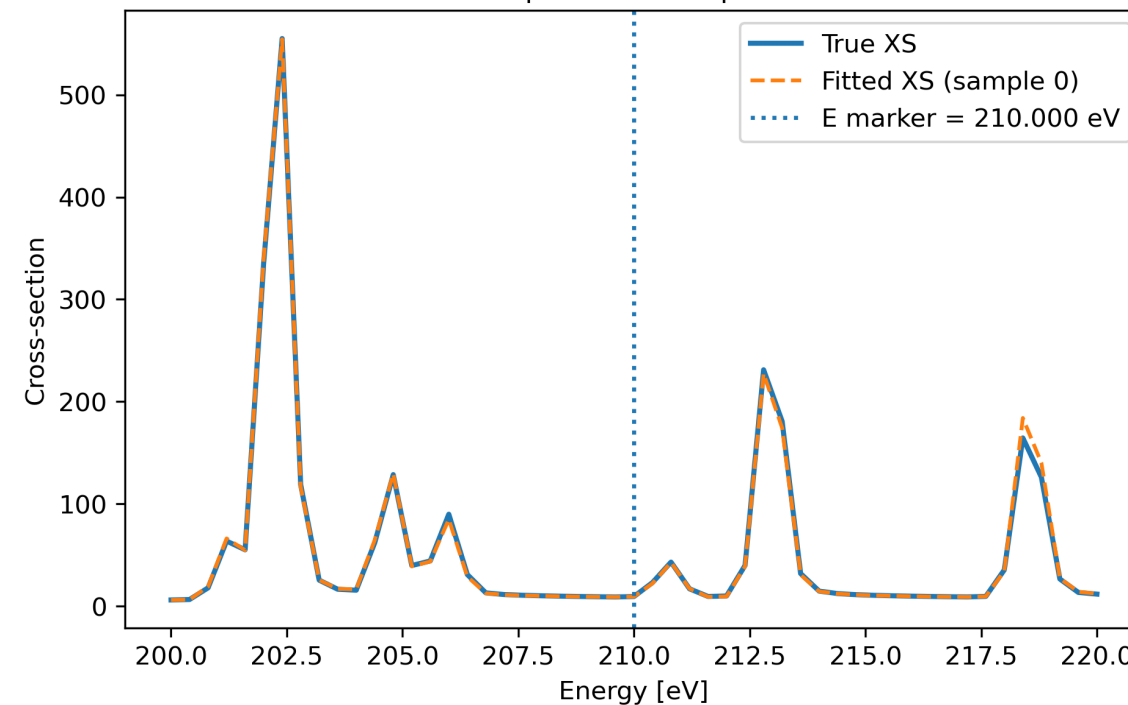
Distribution of Error

Examples

Fitted XS density + LogNormal overlays
ladder 208 | $E \approx 210.000$ eV



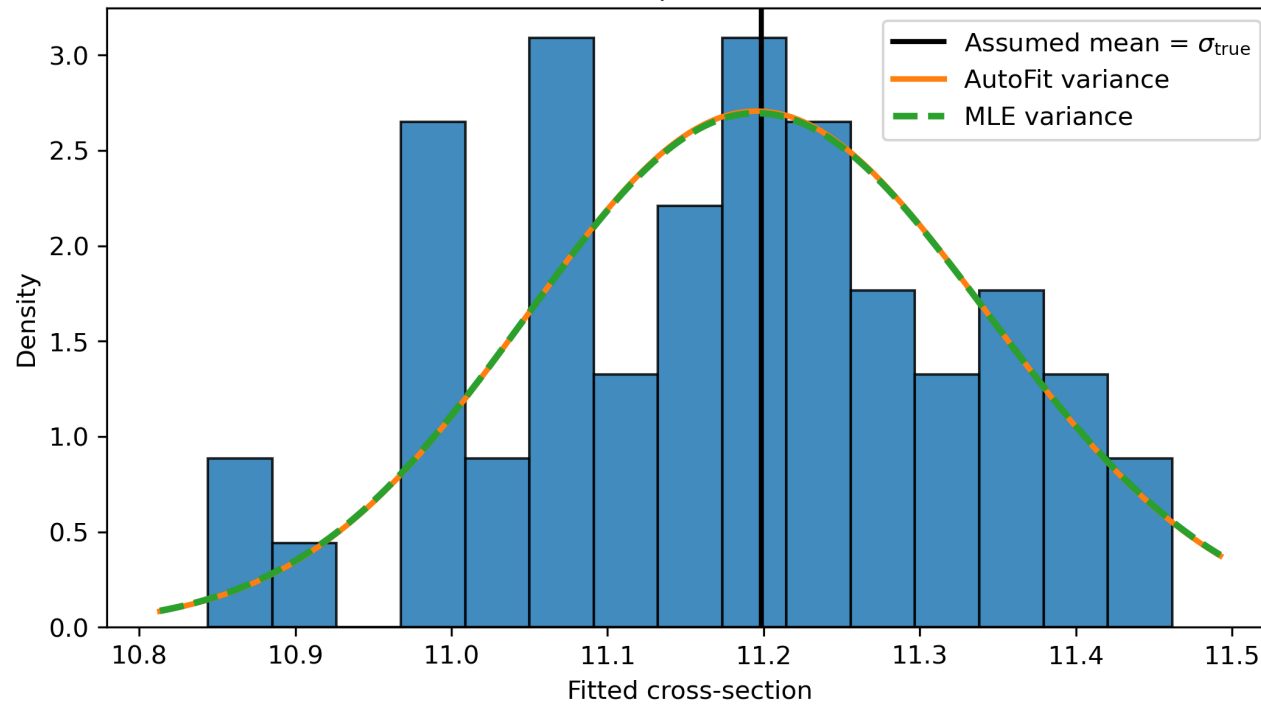
Cross-section | ladder 208 | $E \approx 210.000$ eV



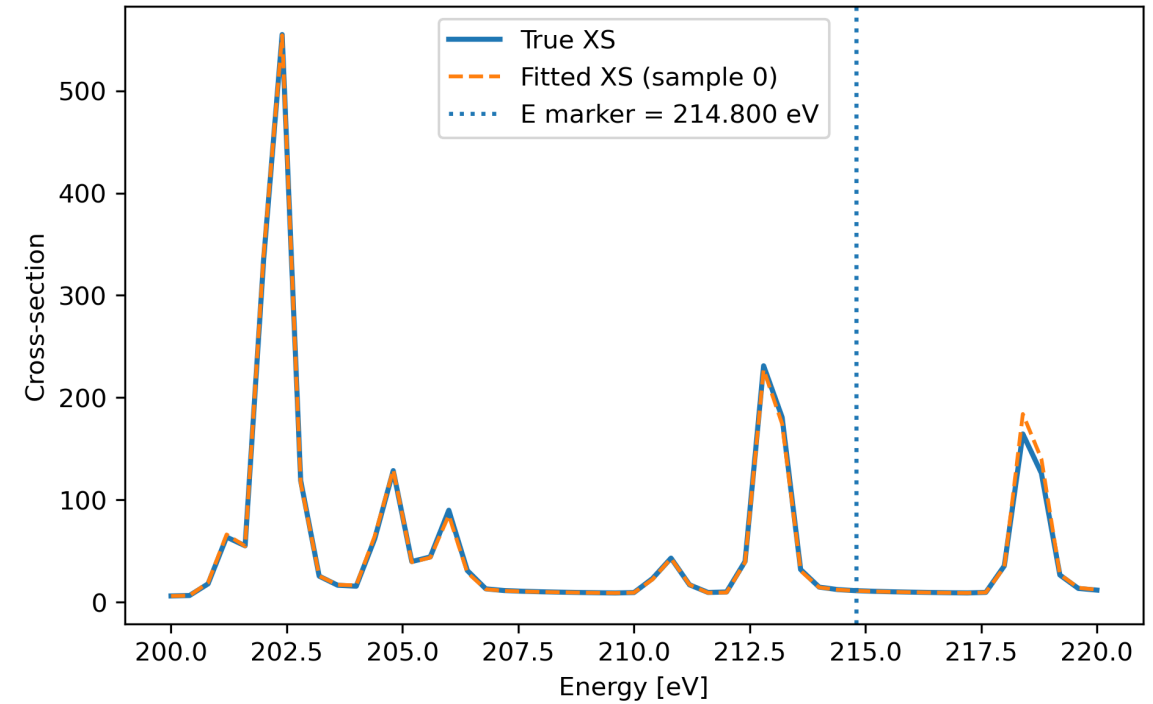
Distribution of Error

Examples

Fitted XS density + LogNormal overlays
ladder 208 | $E \approx 214.800$ eV

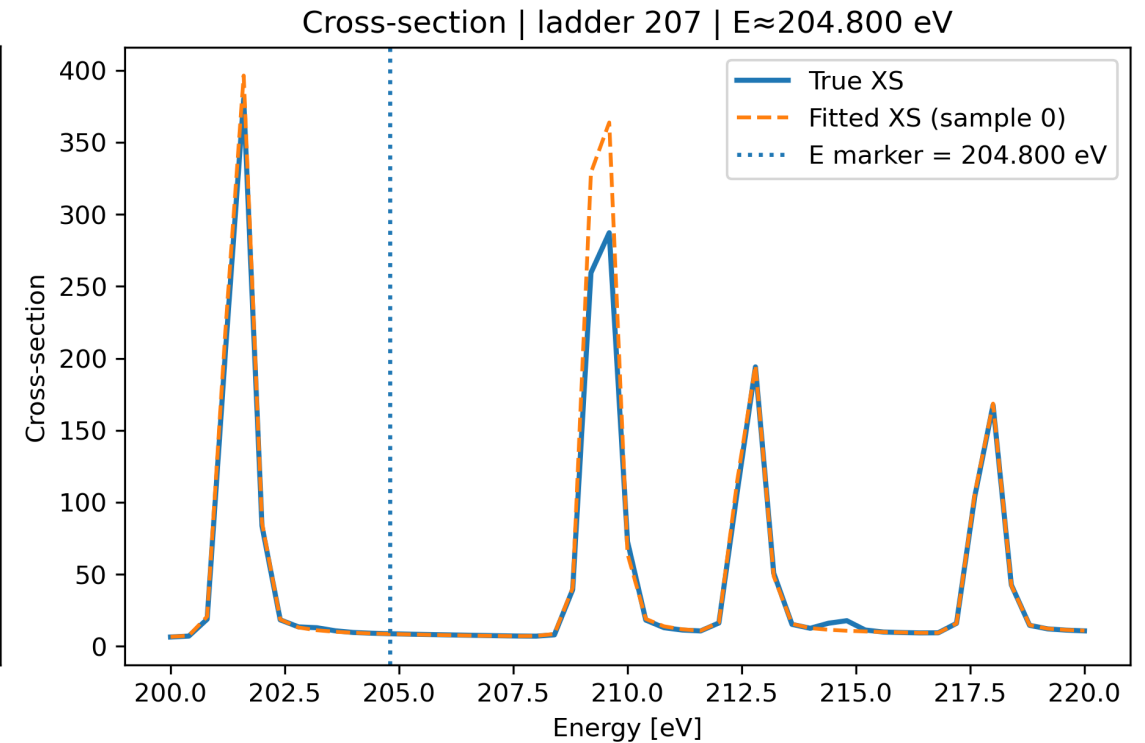
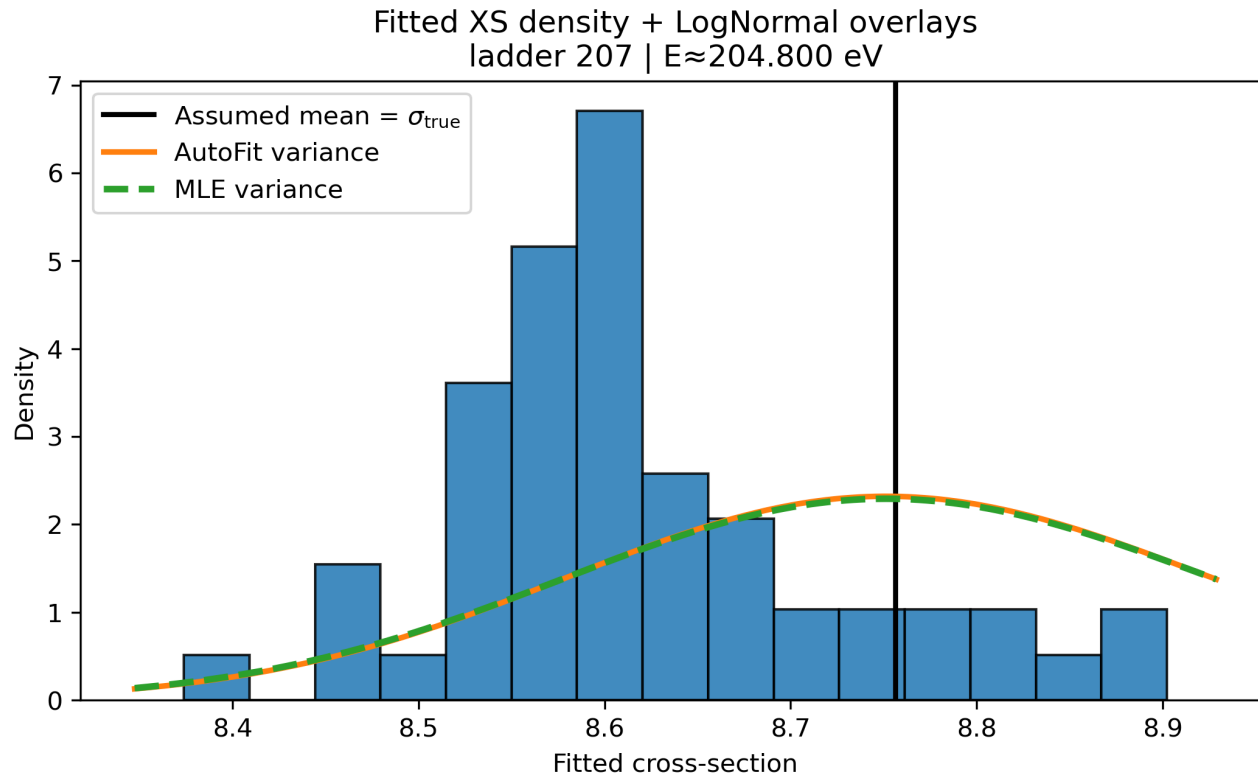


Cross-section | ladder 208 | $E \approx 214.800$ eV



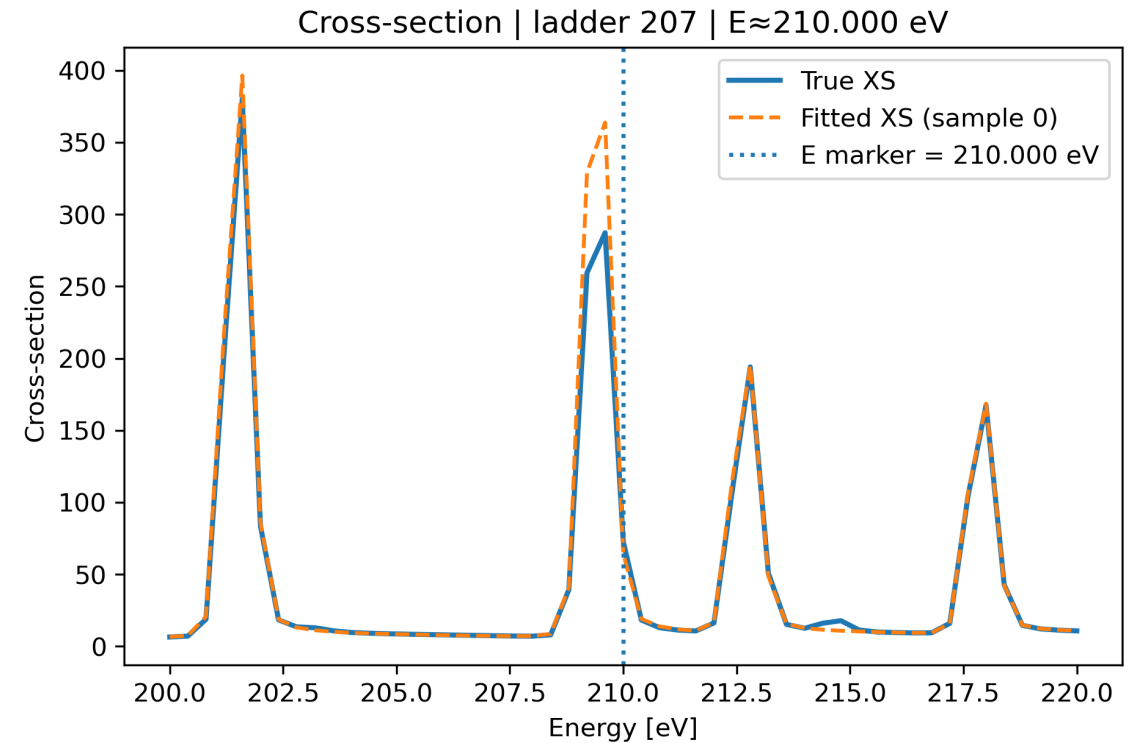
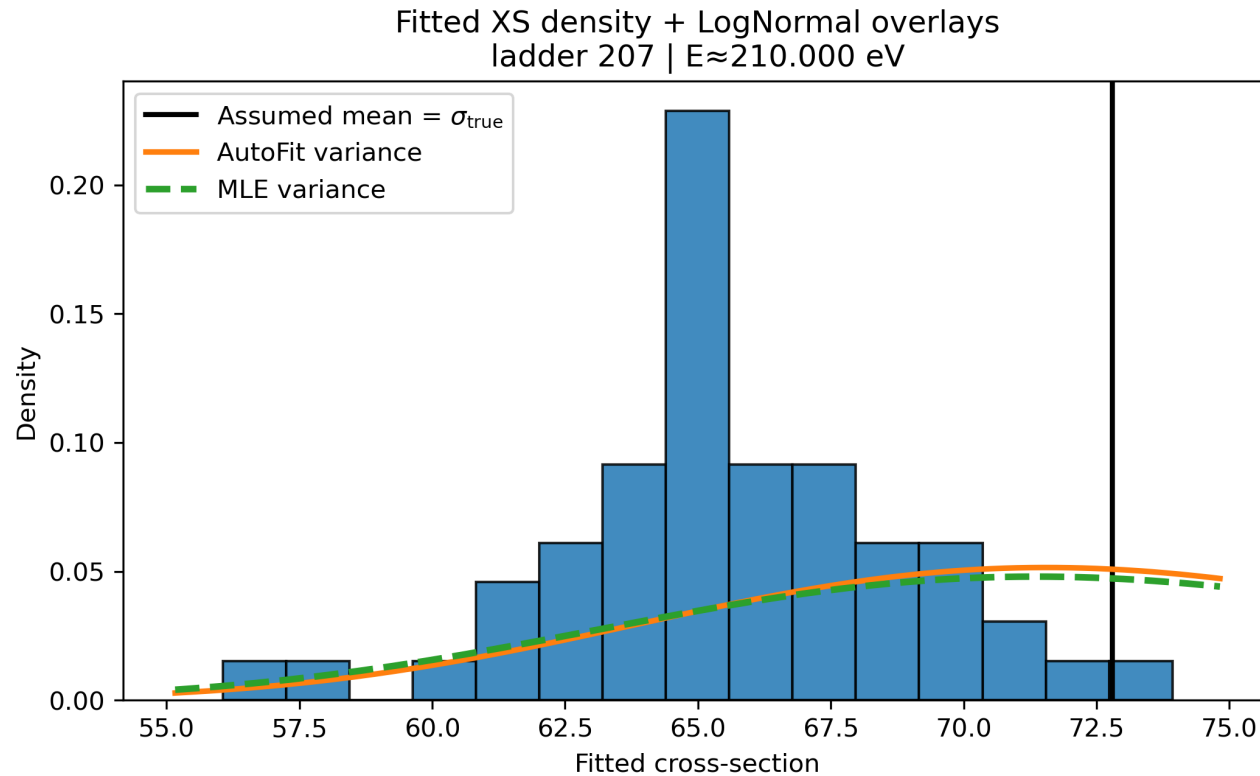
Distribution of Error

Examples



Distribution of Error

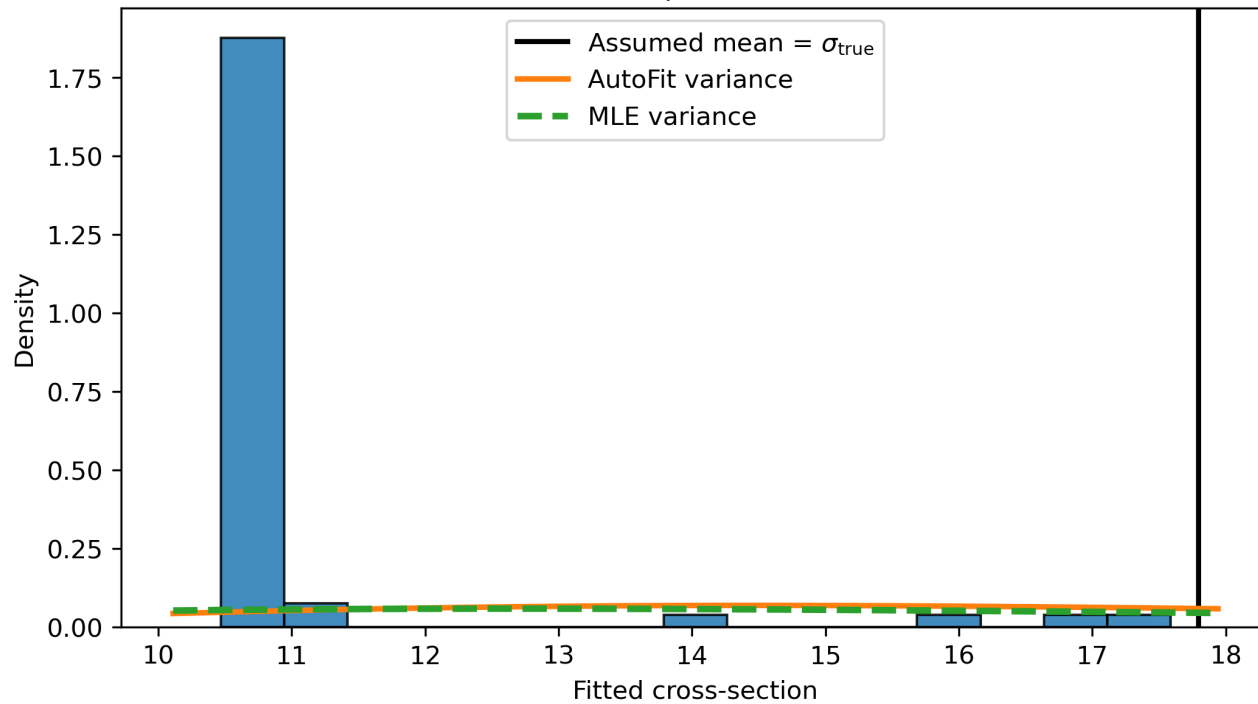
Examples



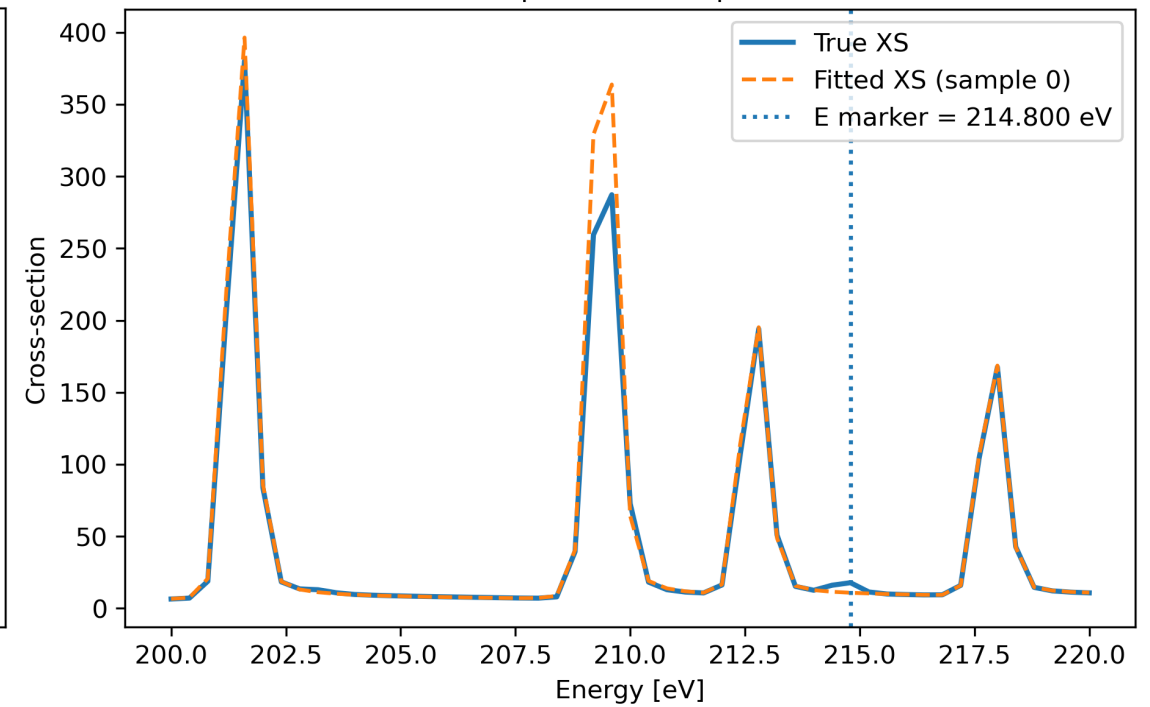
Distribution of Error

Examples

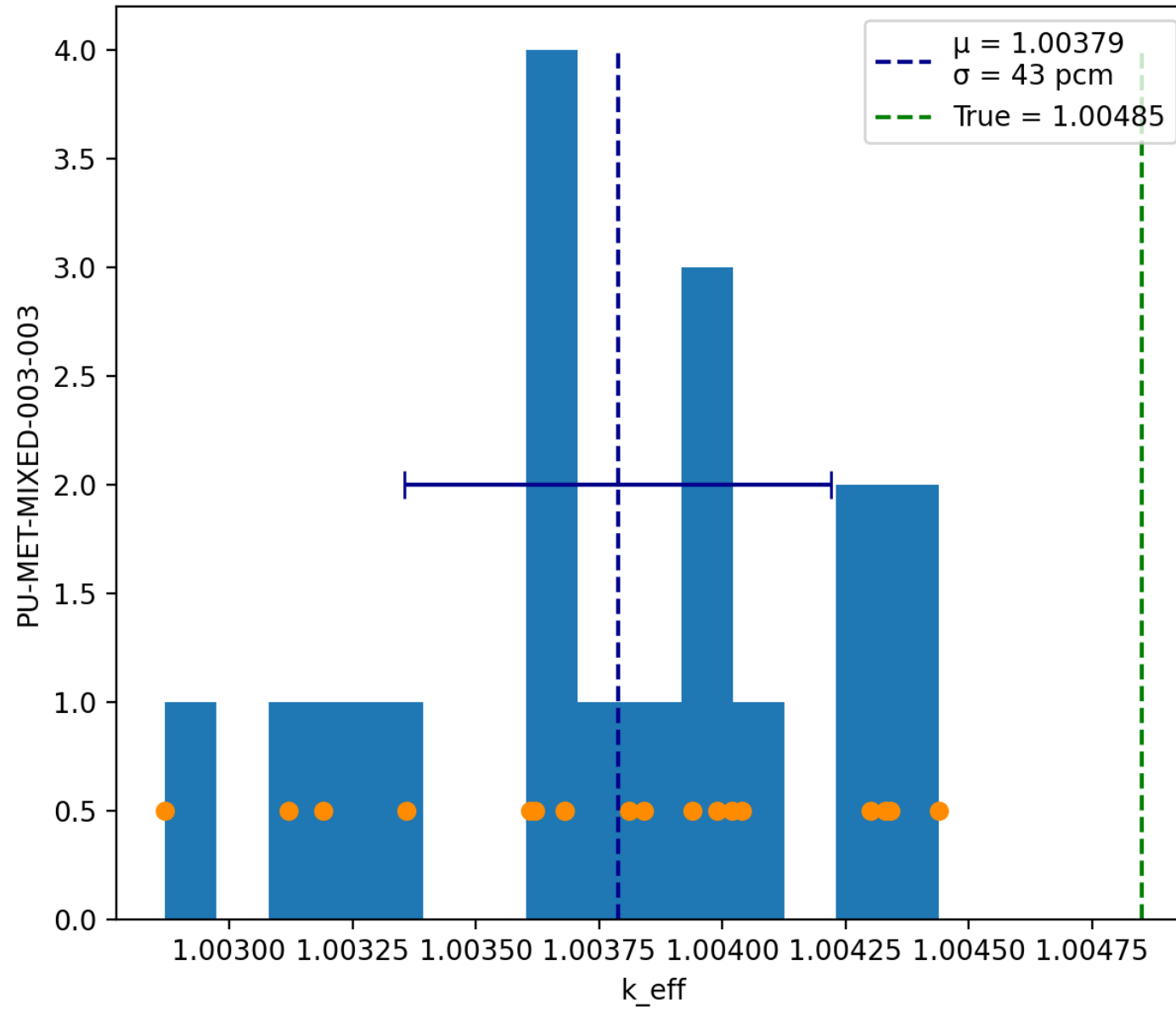
Fitted XS density + LogNormal overlays
ladder 207 | $E \approx 214.800$ eV



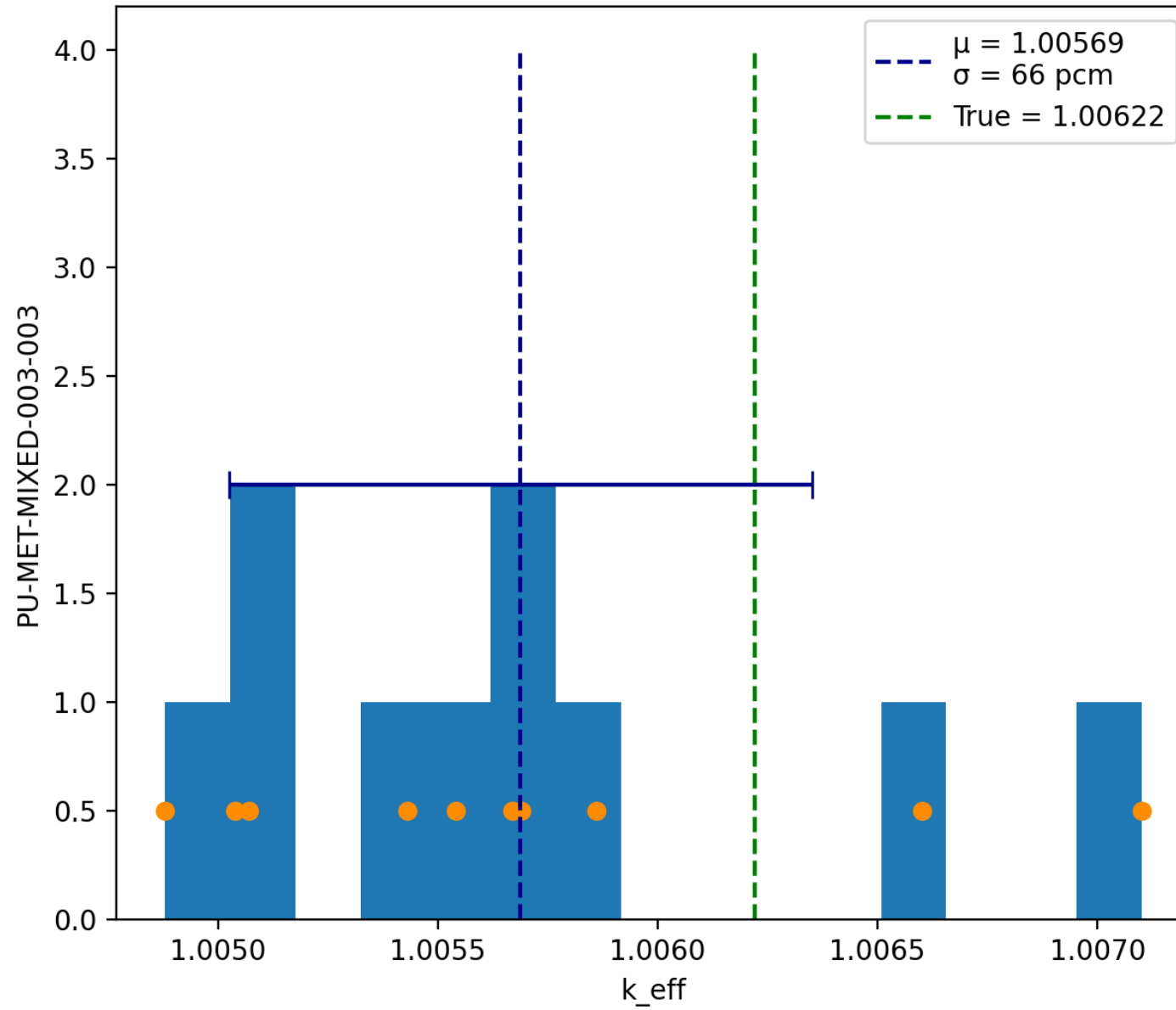
Cross-section | ladder 207 | $E \approx 214.800$ eV



Benchmark Simulation Results
Ta-181 Resonances 200-2500eV Replaced with Syndat
18 Samples Converged to 10 pcm



Benchmark Simulation Results
Ta-181 Resonances 200-2500eV Replaced with Syndat
10 Samples Converged to 10 pcm



Benchmark Simulation Results
Ta-181 Resonances 200-2500eV Replaced with Syndat
9 Samples Converged to 10 pcm

